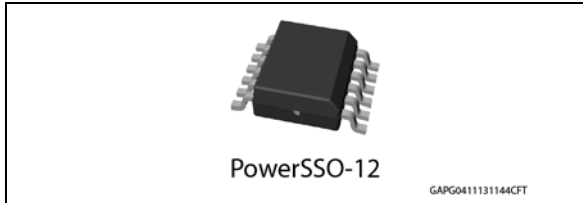


Double channel high-side driver with CurrentSense analog feedback for automotive applications

Datasheet - production data



Features

Max transient supply voltage	V_{CC}	40 V
Operating voltage range	V_{CC}	4 to 28 V
Typ. on-state resistance (per Ch)	R_{ON}	140 m Ω
Current limitation (typ)	I_{LIMH}	12 A
Standby current (max)	I_{STBY}	0.5 μ A

- Automotive qualified
- General
 - Double channel smart high-side driver with CurrentSense analog feedback
 - Very low standby current
 - Compatible with 3 V and 5 V CMOS outputs
- CurrentSense diagnostic functions
 - Multiplexed analog feedback of: load current with high precision proportional current mirror
 - Overload and short to ground (power limitation) indication
 - Thermal shutdown indication
 - OFF-state open-load detection
 - Output short to V_{CC} detection
 - Sense enable/ disable
- Protections
 - Undervoltage shutdown
 - Overvoltage clamp
 - Load current limitation
 - Self limiting of fast thermal transients

- Loss of ground and loss of V_{CC}
- Reverse battery with external components
- Electrostatic discharge protection

Applications

- All types of Automotive resistive, inductive and capacitive loads
- Specially intended for automotive signal lamps (up to R10W or LED Rear Combinations)

Description

The VND7140AJ12-E is a double channel high-side driver manufactured using ST proprietary VIPower[®] technology and housed in PowerSSO-12 package. The device is designed to drive 12 V automotive grounded loads through a 3 V and 5 V CMOS-compatible interface, providing protection and diagnostics.

The device integrates advanced protective functions such as load current limitation, overload active management by power limitation and overtemperature shutdown.

A current sense delivers high precision proportional load current sense in addition to the detection of overload and short circuit to ground, short to V_{CC} and OFF-state open-load.

A sense enable pin allows OFF-state diagnosis to be disabled during the module low-power mode as well as external sense resistor sharing among similar devices.

Contents

1	Block diagram and pin description	6
2	Electrical specification	8
2.1	Absolute maximum ratings	8
2.2	Thermal data	9
2.3	Main electrical characteristics	10
2.4	Waveforms	19
2.5	Electrical characteristics curves	21
3	Protections	25
3.1	Power limitation	25
3.2	Thermal shutdown	25
3.3	Current limitation	25
3.4	Negative voltage clamp	25
4	Application information	26
4.1	GND protection network against reverse battery	26
4.1.1	Diode (DGND) in the ground line	27
4.2	Immunity against transient electrical disturbances	27
4.3	MCU I/Os protection	28
4.4	CurrentSense - analog current sense	28
4.4.1	Principle of CurrentSense signal generation	29
4.4.2	Short to VCC and OFF-state open-load detection	31
4.5	Maximum demagnetization energy ($V_{CC} = 16\text{ V}$)	32
5	Package and PCB thermal data	33
5.1	PowerSSO-12 thermal data	33
6	Package information	36
6.1	ECOPACK [®]	36
6.2	PowerSSO-12 package information	36
7	Order codes	38

8 **Revision history** **39**

List of tables

Table 1.	Pin functions	6
Table 2.	Suggested connections for unused and not connected pins	7
Table 3.	Absolute maximum ratings	8
Table 4.	Thermal data	9
Table 5.	Power section	10
Table 6.	Switching ($V_{CC} = 13\text{ V}$; $-40^{\circ}\text{C} < T_j < 150^{\circ}\text{C}$, unless otherwise specified)	11
Table 7.	Logic Inputs ($7\text{ V} < V_{CC} < 28\text{ V}$; $-40^{\circ}\text{C} < T_j < 150^{\circ}\text{C}$)	11
Table 8.	Protections ($7\text{ V} < V_{CC} < 18\text{ V}$; $-40^{\circ}\text{C} < T_j < 150^{\circ}\text{C}$)	12
Table 9.	CurrentSense ($7\text{ V} < V_{CC} < 18\text{ V}$; $-40^{\circ}\text{C} < T_j < 150^{\circ}\text{C}$)	12
Table 10.	Truth table.	18
Table 11.	CurrentSense multiplexer addressing	19
Table 12.	ISO 7637-2 - electrical transient conduction along supply line	27
Table 13.	CurrentSense pin levels in off-state	31
Table 14.	PCB properties	33
Table 15.	Thermal parameters	35
Table 16.	PowerSSO-12 mechanical data	37
Table 17.	Device summary	38
Table 18.	Revision history	39

List of figures

Figure 1.	Block diagram	6
Figure 2.	Configuration diagram (top view)	7
Figure 3.	Current and voltage conventions	8
Figure 4.	I_{OUT}/I_{SENSE} versus I_{OUT}	16
Figure 5.	Current sense accuracy versus I_{OUT}	16
Figure 6.	Switching times and Pulse skew	17
Figure 7.	CurrentSense timings (current sense mode)	17
Figure 8.	T_{DSTKON}	18
Figure 9.	Standby mode activation	19
Figure 10.	Standby state diagram	20
Figure 11.	OFF-state output current	21
Figure 12.	Standby current	21
Figure 13.	$I_{GND(ON)}$ vs. I_{out}	21
Figure 14.	Logic Input high level voltage	21
Figure 15.	Logic Input low level voltage	22
Figure 16.	High level logic input current	22
Figure 17.	Low level logic input current	22
Figure 18.	Logic Input hysteresis voltage	22
Figure 19.	Undervoltage shutdown	22
Figure 20.	On-state resistance vs. T_{case}	22
Figure 21.	On-state resistance vs. V_{CC}	23
Figure 22.	Turn-on voltage slope	23
Figure 23.	Turn-off voltage slope	23
Figure 24.	W_{on} vs T_{case}	23
Figure 25.	W_{off} vs T_{case}	23
Figure 26.	I_{LIMH} vs. T_{case}	23
Figure 27.	OFF-state open-load voltage detection threshold	24
Figure 28.	V_{sense} clamp vs T_{case}	24
Figure 29.	V_{senseh} vs T_{case}	24
Figure 30.	Application diagram	26
Figure 31.	Simplified internal structure	26
Figure 32.	CurrentSense and diagnostic – block diagram	28
Figure 33.	CurrentSense block diagram	29
Figure 34.	Analogue HSD – open-load detection in off-state	30
Figure 35.	Open-load / short to VCC condition	31
Figure 36.	Maximum turn off current versus inductance	32
Figure 37.	PowerSSO-12 on two-layers PCB (2s0p to JEDEC JESD 51-5)	33
Figure 38.	PowerSSO-12 on four-layers PCB (2s2p to JEDEC JESD 51-7)	33
Figure 39.	PowerSSO-12 $R_{thj-amb}$ vs PCB copper area in open box free air condition	34
Figure 40.	PowerSSO-12 thermal impedance junction ambient single pulse	34
Figure 41.	Thermal fitting model for PowerSSO-12	35
Figure 42.	PowerSSO-12 package dimensions	36

1 Block diagram and pin description

Figure 1. Block diagram

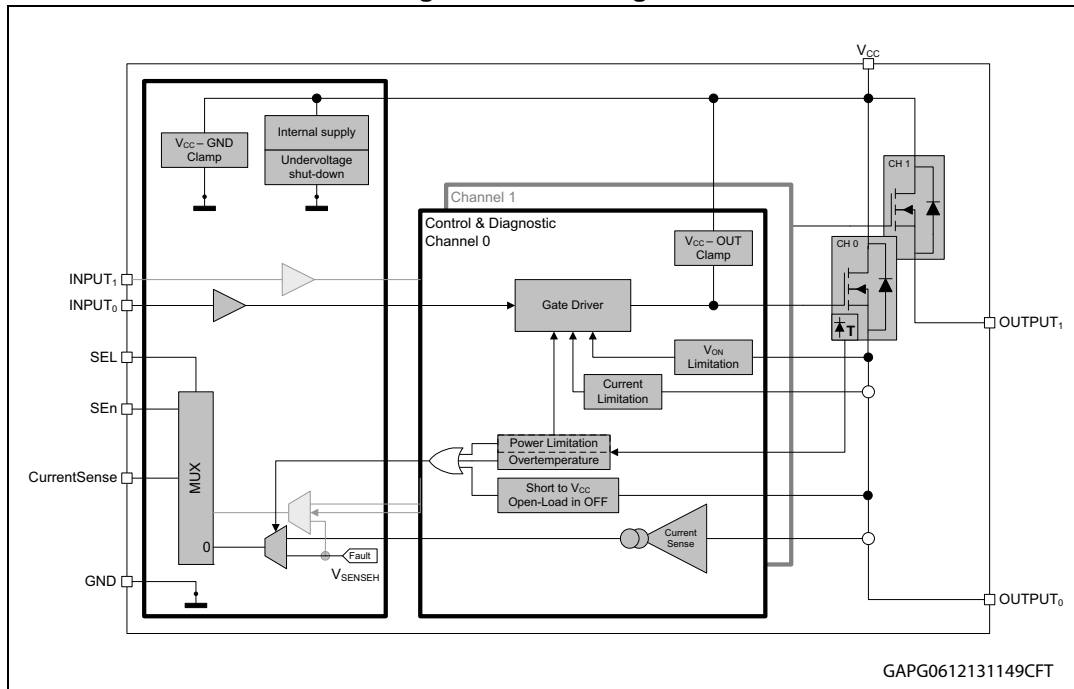


Table 1. Pin functions

Name	Function
V _{CC}	Battery connection.
OUTPUT _{0,1}	Power output.
GND	Ground connection. Must be reverse battery protected by an external diode / resistor network.
INPUT _{0,1}	Voltage controlled input pin with hysteresis, compatible with 3 V and 5 V CMOS outputs. They control output switch state.
CurrentSense	Multiplexed analog sense output pin; it delivers a current proportional to the selected diagnostic: load current, supply voltage or chip temperature.
SEn	Active high compatible with 3 V and 5 V CMOS outputs pin; it enables the CurrentSense diagnostic pin.
SEL	Active high compatible with 3 V and 5 V CMOS outputs pin; it address the CurrentSense multiplexer.

Figure 2. Configuration diagram (top view)

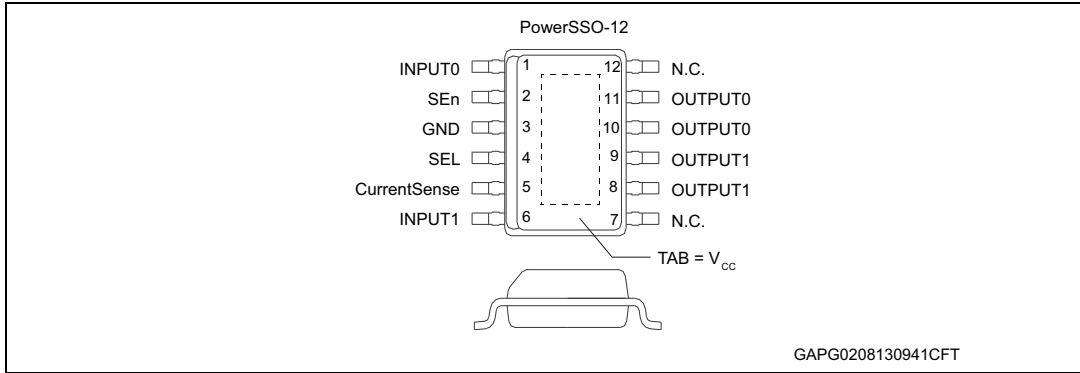


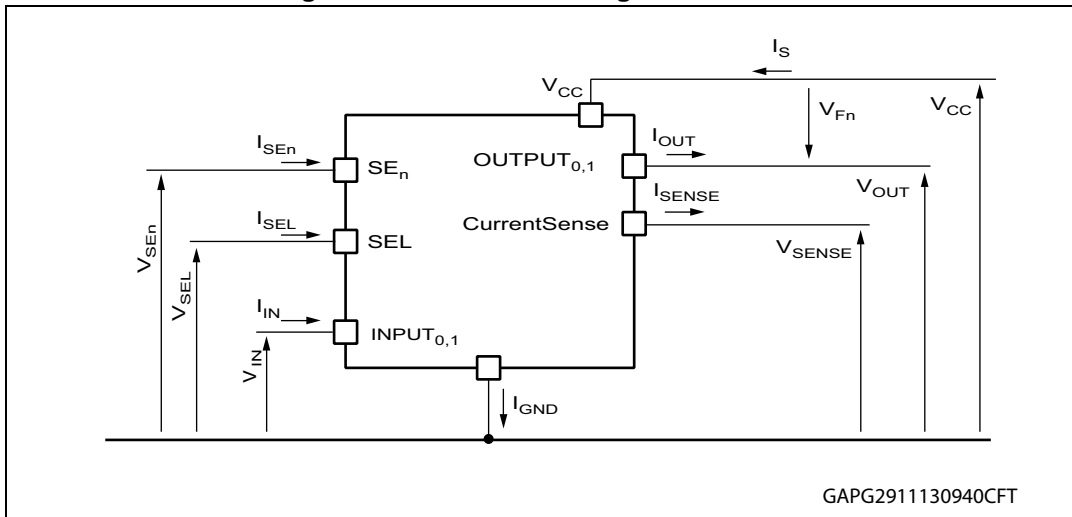
Table 2. Suggested connections for unused and not connected pins

Connection / pin	CurrentSense	N.C.	Output	Input	SEn, SEL
Floating	Not allowed	X ⁽¹⁾	X	X	X
To ground	Through 1 kΩ resistor	X	Not allowed	Through 15 kΩ resistor	Through 15 kΩ resistor

1. X: do not care.

2 Electrical specification

Figure 3. Current and voltage conventions



Note: $V_{Fn} = V_{OUTn} - V_{CC}$ during reverse battery condition.

2.1 Absolute maximum ratings

Stressing the device above the rating listed in [Table 3](#) may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the operating sections of this specification is not implied. Exposure to the conditions in table below for extended periods may affect device reliability.

Table 3. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{CC}	DC supply voltage	38	V
$-V_{CC}$	Reverse DC supply voltage	0.3	
V_{CCPK}	Maximum transient supply voltage (ISO 16750-2:2010 Test B clamped to 40V; $R_L = 4 \Omega$)	40	V
V_{CCJS}	Maximum jump start voltage for single pulse short circuit protection	28	V
$-I_{GND}$	DC reverse ground pin current	200	mA
I_{OUT}	OUTPUT _{0,1} DC output current	Internally limited	A
$-I_{OUT}$	Reverse DC output current	4	
I_{IN}	INPUT _{0,1} DC input current	-1 to 10	mA
I_{SEn}	SEn DC input current		
I_{SEL}	SEL DC input current		

Table 3. Absolute maximum ratings (continued)

Symbol	Parameter	Value	Unit
I _{SENSE}	CurrentSense pin DC output current (V _{GND} = V _{CC} and V _{SENSE} < 0 V)	10	mA
	CurrentSense pin DC output current in reverse (V _{CC} < 0 V)	-20	
E _{MAX}	Maximum switching energy (single pulse) (T _{DEMAG} = 0.4 ms; T _{jstart} = 150 °C)	10	mJ
V _{ESD}	Electrostatic discharge (JEDEC 22A-114F)		
	– INPUT _{0,1}	4000	V
	– CurrentSense	2000	V
	– SE _n , SEL	4000	V
	– OUTPUT _{0,1}	4000	V
	– V _{CC}	4000	V
V _{ESD}	Charge device model (CDM-AEC-Q100-011)	750	V
T _j	Junction operating temperature	- 40 to 150	°C
T _{stg}	Storage temperature	- 55 to 150	

2.2 Thermal data

Table 4. Thermal data

Symbol	Parameter	Typ. value	Unit
R _{thj-board}	Thermal resistance junction-board (JEDEC JESD 51-5/15-8) ⁽¹⁾⁽²⁾	7.7	°C/W
R _{thj-amb}	Thermal resistance junction-ambient (JEDEC JESD 51-5) ⁽¹⁾⁽³⁾	61	
R _{thj-amb}	Thermal resistance junction-ambient (JEDEC JESD 51-7) ⁽¹⁾⁽²⁾	26.5	

- One channel ON.
- Device mounted on four-layers 2s2p PCB.
- Device mounted on two-layers 2s0p PCB with 2 cm² heatsink copper trace.

2.3 Main electrical characteristics

$7\text{ V} < V_{CC} < 28\text{ V}$; $-40\text{ °C} < T_j < 150\text{ °C}$, unless otherwise specified.

All typical values refer to $V_{CC} = 13\text{ V}$; $T_j = 25\text{ °C}$, unless otherwise specified.

Table 5. Power section

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V_{CC}	Operating supply voltage		4	13	28	V
V_{USD}	Undervoltage shutdown				4	
$V_{USDReset}$	Undervoltage shutdown reset				5	
$V_{USDhyst}$	Undervoltage shutdown hysteresis			0.3		
R_{ON}	On-state resistance ⁽¹⁾	$I_{OUT} = 1\text{ A}$; $T_j = 25\text{ °C}$		140		mΩ
		$I_{OUT} = 1\text{ A}$; $T_j = 150\text{ °C}$			280	
		$I_{OUT} = 1\text{ A}$; $V_{CC} = 4\text{ V}$; $T_j = 25\text{ °C}$			210	
V_{clamp}	Clamp voltage	$I_S = 20\text{ mA}$; $T_j = -40\text{ °C}$	38			V
		$I_S = 20\text{ mA}$; $25\text{ °C} < T_j < 150\text{ °C}$	41	46	52	
I_{STBY}	Supply current in standby at $V_{CC} = 13\text{ V}$ ⁽²⁾	$V_{CC} = 13\text{ V}$; $V_{IN} = V_{OUT} = V_{SEn} = 0\text{ V}$; $V_{SEL} = 0\text{ V}$; $T_j = 25\text{ °C}$			0.5	μA
		$V_{CC} = 13\text{ V}$; $V_{IN} = V_{OUT} = V_{SEn} = 0\text{ V}$; $V_{SEL} = 0\text{ V}$; $T_j = 85\text{ °C}$ ⁽³⁾			0.5	μA
		$V_{CC} = 13\text{ V}$; $V_{IN} = V_{OUT} = V_{SEn} = 0\text{ V}$; $V_{SEL} = 0\text{ V}$; $T_j = 125\text{ °C}$			3	μA
t_{D_STBY}	Standby mode blanking time	$V_{CC} = 13\text{ V}$; $V_{IN} = V_{OUT} = V_{SEL} = 0\text{ V}$; $V_{SEn} = 5\text{ V to }0\text{ V}$	60	300	550	μA
$I_{S(ON)}$	Supply current	$V_{CC} = 13\text{ V}$; $V_{SEn} = V_{SEL} = 0\text{ V}$; $V_{IN0} = 5\text{ V}$; $V_{IN1} = 5\text{ V}$; $I_{OUT0} = 0\text{ A}$; $I_{OUT1} = 0\text{ A}$		5	8	mA
$I_{GND(ON)}$	Control stage current consumption in ON state. All channels active.	$V_{CC} = 13\text{ V}$; $V_{SEn} = 5\text{ V}$; $V_{SEL} = 0\text{ V}$; $V_{IN0} = 5\text{ V}$; $V_{IN1} = 5\text{ V}$; $I_{OUT0} = 1\text{ A}$; $I_{OUT1} = 1\text{ A}$			12	mA
$I_{L(off)}$	Off-state output current at $V_{CC} = 13\text{ V}$ ⁽¹⁾	$V_{IN} = V_{OUT} = 0\text{ V}$; $V_{CC} = 13\text{ V}$; $T_j = 25\text{ °C}$	0	0.01	0.5	μA
		$V_{IN} = V_{OUT} = 0\text{ V}$; $V_{CC} = 13\text{ V}$; $T_j = 125\text{ °C}$	0		3	
V_F	Output - V_{CC} diode voltage ⁽¹⁾	$I_{OUT} = -1\text{ A}$; $T_j = 150\text{ °C}$			0.7	V

1. For each channel
2. PowerMOS leakage included.
3. Parameter specified by design; not subject to production test.

Table 6. Switching ($V_{CC} = 13\text{ V}$; $-40^{\circ}\text{C} < T_j < 150^{\circ}\text{C}$, unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}^{(1)}$	Turn-on delay time at $T_j = 25^{\circ}\text{C}$	$R_L = 13\ \Omega$	10	70	120	μs
$t_{d(off)}^{(1)}$	Turn-off delay time at $T_j = 25^{\circ}\text{C}$		10	40	100	
$(dV_{OUT}/dt)_{on}^{(1)}$	Turn-on voltage slope at $T_j = 25^{\circ}\text{C}$	$R_L = 13\ \Omega$	0.1	0.27	0.7	$\text{V}/\mu\text{s}$
$(dV_{OUT}/dt)_{off}^{(1)}$	Turn-off voltage slope at $T_j = 25^{\circ}\text{C}$		0.1	0.35	0.7	
W_{ON}	Switching energy losses at turn-on (t_{won})	$R_L = 13\ \Omega$	—	0.15	0.18 ⁽²⁾	mJ
W_{OFF}	Switching energy losses at turn-off (t_{woff})	$R_L = 13\ \Omega$	—	0.1	0.18 ⁽²⁾	mJ
$t_{SKEW}^{(1)}$	Differential Pulse skew ($t_{PHL} - t_{PLH}$)	$R_L = 13\ \Omega$	-100	-50	0	μs

1. See [Figure 6: Switching times and Pulse skew](#).
2. Parameter guaranteed by design and characterization; not subject to production test.

Table 7. Logic Inputs ($7\text{ V} < V_{CC} < 28\text{ V}$; $-40^{\circ}\text{C} < T_j < 150^{\circ}\text{C}$)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
INPUT_{0,1} characteristics						
V_{IL}	Input low level voltage				0.9	V
I_{IL}	Low level input current	$V_{IN} = 0.9\text{ V}$	1			μA
V_{IH}	Input high level voltage		2.1			V
I_{IH}	High level input current	$V_{IN} = 2.1\text{ V}$			10	μA
$V_{I(hyst)}$	Input hysteresis voltage		0.2			V
V_{ICL}	Input clamp voltage	$I_{IN} = 1\text{ mA}$	5.3		7.2	V
		$I_{IN} = -1\text{ mA}$		-0.7		
SEL characteristics ($7\text{ V} < V_{CC} < 18\text{ V}$)						
V_{SELL}	Input low level voltage				0.9	V
I_{SELL}	Low level input current	$V_{IN} = 0.9\text{ V}$	1			μA
V_{SELH}	Input high level voltage		2.1			V
I_{SELH}	High level input current	$V_{IN} = 2.1\text{ V}$			10	μA
$V_{SEL(hyst)}$	Input hysteresis voltage		0.2			V
V_{SELCL}	Input clamp voltage	$I_{IN} = 1\text{ mA}$	5.3		7.2	V
		$I_{IN} = -1\text{ mA}$		-0.7		
SEn characteristics ($7\text{ V} < V_{CC} < 18\text{ V}$)						
V_{SEnL}	Input low level voltage				0.9	V
I_{SEnL}	Low level input current	$V_{IN} = 0.9\text{ V}$	1			μA

Table 7. Logic Inputs (7 V < V_{CC} < 28 V; -40°C < T_j < 150°C) (continued)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V _{SEnH}	Input high level voltage		2.1			V
I _{SEnH}	High level input current	V _{IN} = 2.1 V			10	μA
V _{SEn(hyst)}	Input hysteresis voltage		0.2			V
V _{SEnCL}	Input clamp voltage	I _{IN} = 1 mA	5.3		7.2	V
		I _{IN} = -1 mA		-0.7		

Table 8. Protections (7 V < V_{CC} < 18 V; -40 °C < T_j < 150 °C)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I _{LIMH}	DC short circuit current	V _{CC} = 13 V	8	12	16	A
		4 V < V _{CC} < 18 V ⁽¹⁾			16	
I _{LIML}	Short circuit current during thermal cycling	V _{CC} = 13 V; T _R < T _j < T _{TSD}		4		
T _{TSD}	Shutdown temperature		150	175	200	°C
T _R	Reset temperature ⁽¹⁾		T _{RS} + 1	T _{RS} + 7		°C
T _{RS}	Thermal reset of fault diagnostic indication	V _{SEn} = 5 V	135			°C
T _{HYST}	Thermal hysteresis (T _{TSD} - T _R) ⁽¹⁾			7		°C
ΔT _{J_SD}	Dynamic temperature	T _j = -40 °C; V _{CC} = 13 V		60		K
V _{DEMAG}	Turn-off output voltage clamp	I _{OUT} = 1 A; L = 6 mH; T _j = -40 °C	V _{CC} - 38			V
		I _{OUT} = 1 A; L = 6 mH; T _j = 25 °C to 150 °C	V _{CC} - 41	V _{CC} - 46	V _{CC} - 52	V
V _{ON}	Output voltage drop limitation	I _{OUT} = 0.07 A		20		mV

1. Parameter guaranteed by design and characterization; not subject to production test.

Table 9. CurrentSense (7 V < V_{CC} < 18 V; -40°C < T_j < 150°C)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V _{SENSE_CL}	CurrentSense clamp voltage	V _{SEn} = 0 V; I _{SENSE} = 1 mA	-17		-12	V
		V _{SEn} = 0 V; I _{SENSE} = -1 mA		7		
Current Sense characteristics						
K _{OL}	I _{OUT} /I _{SENSE}	I _{OUT} = 0.01 A; V _{SENSE} = 0.5 V; V _{SEn} = 5 V	275			
dK _{cal} /K _{cal} ⁽¹⁾⁽²⁾	Current sense ratio drift at calibration point	I _{OUT} = 0.01 A to 0.025 A; I _{cal} = 17.5 mA; V _{SENSE} = 0.5 V; V _{SEn} = 5 V	-30		30	%

Table 9. CurrentSense (7 V < V_{CC} < 18 V; -40°C < T_j < 150°C) (continued)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
K _{LED}	I _{OUT} /I _{SENSE}	I _{OUT} = 0.025 A; V _{SENSE} = 0.5 V; V _{SEn} = 5 V	290	580	775	
dK _{LED} /K _{LED} ⁽¹⁾⁽²⁾	Current sense ratio drift	I _{OUT} = 0.025 A; V _{SENSE} = 0.5 V; V _{SEn} = 5 V	-25		25	%
K ₀	I _{OUT} /I _{SENSE}	I _{OUT} = 0.07 A; V _{SENSE} = 0.5 V; V _{SEn} = 5 V	325	550	700	
dK ₀ /K ₀ ⁽¹⁾⁽²⁾	Current sense ratio drift	I _{OUT} = 0.07 A; V _{SENSE} = 0.5 V; V _{SEn} = 5 V	-20		20	%
K ₁	I _{OUT} /I _{SENSE}	I _{OUT} = 0.15 A; V _{SENSE} = 4 V; V _{SEn} = 5 V	325	500	645	
dK ₁ /K ₁ ⁽¹⁾⁽²⁾	Current sense ratio drift	I _{OUT} = 0.15 A; V _{SENSE} = 4 V; V _{SEn} = 5 V	-15		15	%
K ₂	I _{OUT} /I _{SENSE}	I _{OUT} = 0.7 A; V _{SENSE} = 4 V; V _{SEn} = 5 V	380	475	570	
dK ₂ /K ₂ ⁽¹⁾⁽²⁾	Current sense ratio drift	I _{OUT} = 0.7 A; V _{SENSE} = 4 V; V _{SEn} = 5 V	-10		10	%
K ₃	I _{OUT} /I _{SENSE}	I _{OUT} = 2 A; V _{SENSE} = 4 V; V _{SEn} = 5 V	430	470	520	
dK ₃ /K ₃ ⁽¹⁾⁽²⁾	Current sense ratio drift	I _{OUT} = 2 A; V _{SENSE} = 4 V; V _{SEn} = 5 V	-5		5	%
I _{SENSE0}	CurrentSense leakage current	CurrentSense disabled: V _{SEn} = 0 V	0		0.5	μA
		CurrentSense disabled: -1 V < V _{SENSE} < 5 V ⁽¹⁾	-0.5		0.5	
		CurrentSense enabled: V _{SEn} = 5 V; All channels ON; I _{OUTX} = 0 A; Ch _X diagnostic selected; – E.g. Ch ₀ : V _{IN0} = 5 V; V _{IN1} = 5 V; V _{SEL} = 0 V; I _{OUT0} = 0 A; I _{OUT1} = 1 A	0		2	
		CurrentSense enabled: V _{SEn} = 5 V; Ch _X OFF; Ch _X diagnostic selected: – E.g. Ch ₀ : V _{IN0} = 0 V; V _{IN1} = 5 V; V _{SEL} = 0 V; I _{OUT1} = 1 A	0		2	
V _{OUT_MSD} ⁽¹⁾	Output Voltage for CurrentSense shutdown	V _{SEn} = 5 V; R _{SENSE} = 2.7 kΩ – E.g. Ch ₀ : V _{IN0} = 5 V; V _{SEL} = 0 V; I _{OUT0} = 1 A		5		V

Table 9. CurrentSense (7 V < V_{CC} < 18 V; -40°C < T_j < 150°C) (continued)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V _{SENSE_SAT}	CurrentSense saturation voltage	V _{CC} = 7 V; R _{SENSE} = 2.7 kΩ; V _{SEn} = 5 V; V _{IN0} = 5 V; V _{SEL} = 0 V; I _{OUT0} = 2 A; T _j = 150°C	5			V
I _{SENSE_SAT} ⁽¹⁾	CS saturation current	V _{CC} = 7 V; V _{SENSE} = 4 V; V _{IN0} = 5 V; V _{SEn} = 5 V; V _{SEL} = 0 V; T _j = 150°C	4			mA
I _{OUT_SAT} ⁽¹⁾	Output saturation current	V _{CC} = 7 V; V _{SENSE} = 4 V; V _{IN0} = 5 V; V _{SEn} = 5 V; V _{SEL} = 0 V; T _j = 150°C	2.2			A
OFF-state diagnostic						
V _{OL}	OFF-state open-load voltage detection threshold	V _{SEn} = 5 V; Ch _X OFF; Ch _X diagnostic selected: – E.g: Ch ₀ V _{IN0} = 0 V; V _{SEL} = 0 V	2	3	4	V
I _{L(off2)}	OFF-state output sink current	V _{IN} = 0 V; V _{OUT} = V _{OL} ; T _j = -40°C to 125°C	-100		-15	μA
t _{DSTKON}	OFF-state diagnostic delay time from falling edge of INPUT (see Figure 8)	V _{SEn} = 5 V; Ch _X ON to OFF transition Ch _X diagnostic selected: – E.g: Ch ₀ V _{IN0} = 5 V to 0 V; V _{SEL} = 0 V; I _{OUT0} = 0 A; V _{OUT} = 4 V	100	350	700	μs
t _{D_OL_V}	Settling time for valid OFF-state open load diagnostic indication from rising edge of SE _n	V _{IN0} = 0 V; V _{IN1} = 0 V; V _{SEL} = 0 V; V _{OUT0} = 4 V; V _{SEn} = 0 V to 5 V			60	μs
t _{D_VOL}	OFF-state diagnostic delay time from rising edge of V _{OUT}	V _{SEn} = 5 V; Ch _X OFF; Ch _X diagnostic selected – E.g: Ch ₀ V _{IN0} = 0 V; V _{SEL} = 0 V; V _{OUT} = 0 V to 4 V		5	30	μs
Fault diagnostic feedback (see Table 10)						
V _{SENSEH}	CurrentSense output voltage in fault condition	V _{CC} = 13 V; R _{SENSE} = 1 kΩ; – E.g: Ch ₀ in open load V _{IN0} = 0 V; V _{SEn} = 5 V; V _{SEL} = 0 V; I _{OUT0} = 0 A; V _{OUT} = 4 V	5		6.6	V
I _{SENSEH}	CurrentSense output current in fault condition ⁽²⁾	V _{CC} = 13 V; V _{SENSE} = 5 V	7	20	30	mA

Table 9. CurrentSense (7 V < V_{CC} < 18 V; -40°C < T_j < 150°C) (continued)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
CurrentSense timings (current sense mode - see Figure 7)						
t _{DSENSE1H}	Current sense settling time from rising edge of SEn	V _{IN} = 5 V; V _{SEn} = 0 V to 5 V; R _{SENSE} = 1 kΩ; R _L = 13 Ω			60	μs
t _{DSENSE1L}	Current sense disable delay time from falling edge of SEn	V _{IN} = 5 V; V _{SEn} = 5 V to 0 V; R _{SENSE} = 1 kΩ; R _L = 13 Ω		5	20	μs
t _{DSENSE2H}	Current sense settling time from rising edge of INPUT	V _{IN} = 0 V to 5 V; V _{SEn} = 5 V; R _{SENSE} = 1 kΩ; R _L = 13 Ω		100	250	μs
Δt _{DSENSE2H}	Current sense settling time from rising edge of I _{OUT} (dynamic response to a step change of I _{OUT})	V _{IN} = 5 V; V _{SEn} = 5 V; R _{SENSE} = 1 kΩ; I _{SENSE} = 90 % of I _{SENSEMAX} ; R _L = 13 Ω			100	μs
t _{DSENSE2L}	Current sense turn-off delay time from falling edge of INPUT	V _{IN} = 5 V to 0 V; V _{SEn} = 5 V; R _{SENSE} = 1 kΩ; R _L = 13 Ω		50	250	μs
CurrentSense timings (Multiplexer transition times)⁽³⁾						
t _{D_XtoY}	CurrentSense transition delay from Ch _X to Ch _Y	V _{IN0} = 5 V; V _{IN1} = 5 V; V _{SEn} = 5 V; V _{SEL} = 0 V to 5 V; I _{OUT0} = 0A; I _{OUT1} = 1A; R _{SENSE} = 1 kΩ			20	μs
t _{D_CSstoVSENSEH}	CurrentSense transition delay from stable current sense on Ch _X to V _{SENSEH} on Ch _Y	V _{IN0} = 5 V; V _{IN1} = 0 V; V _{SEn} = 5 V; V _{SEL} = 0 V to 5 V; I _{OUT0} = 1 A; V _{OUT1} = 4 V; R _{SENSE} = 1 kΩ			60	μs

1. Parameter specified by design; not subject to production test.
2. All values refer to V_{CC} = 13 V; T_j = 25°C, unless otherwise specified.
3. Transition delay are measured up to +/- 10% of final conditions.

Figure 4. I_{OUT}/I_{SENSE} versus I_{OUT}

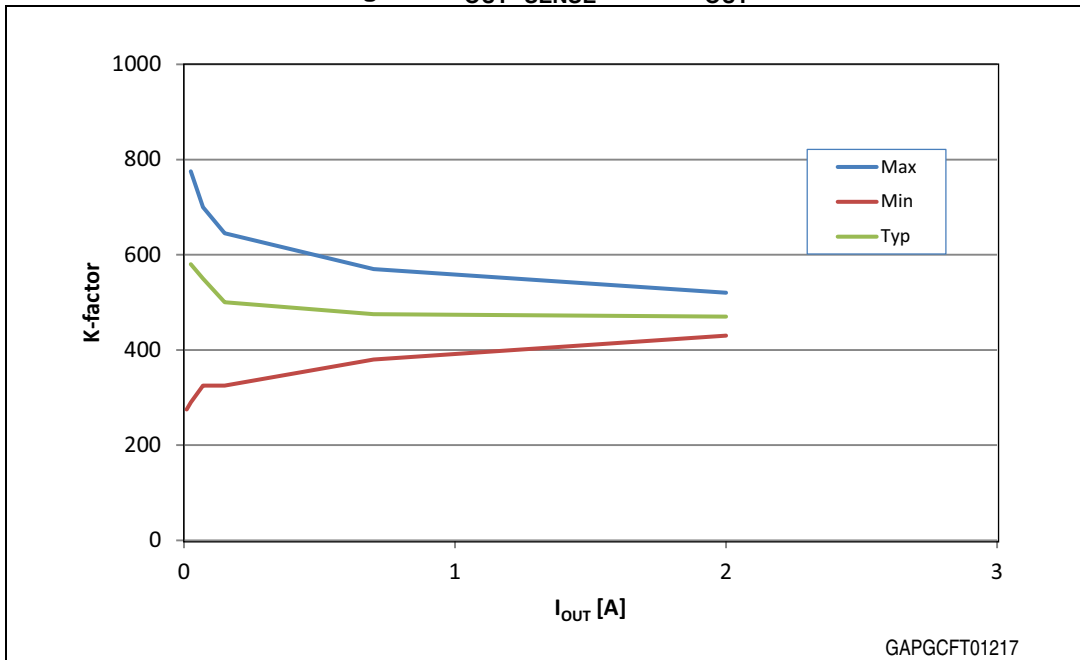


Figure 5. Current sense accuracy versus I_{OUT}

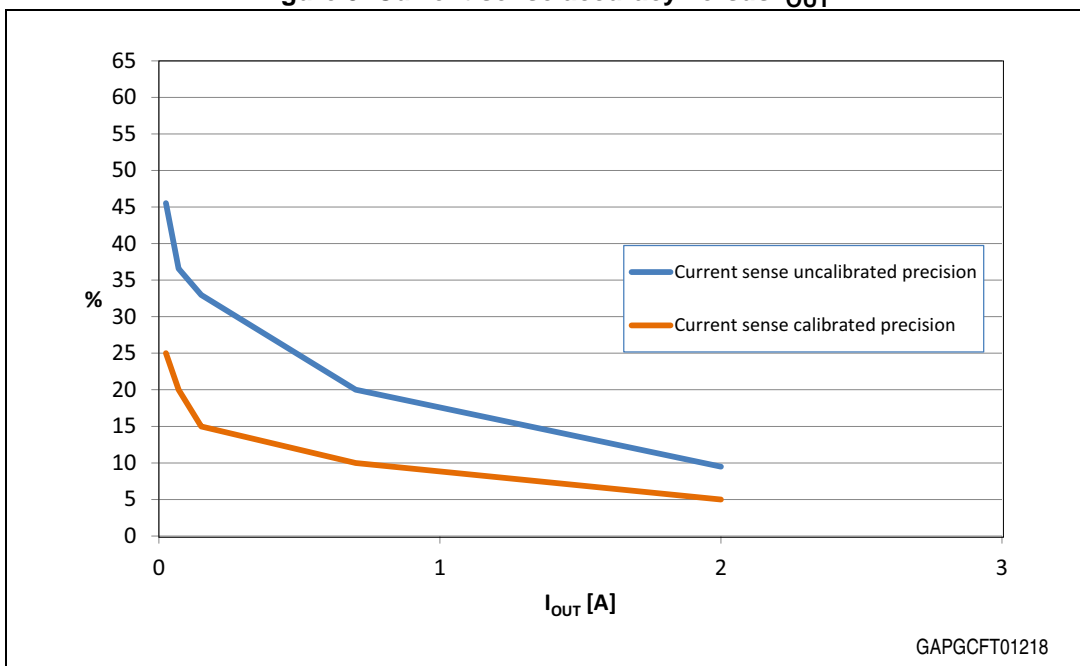


Figure 6. Switching times and Pulse skew

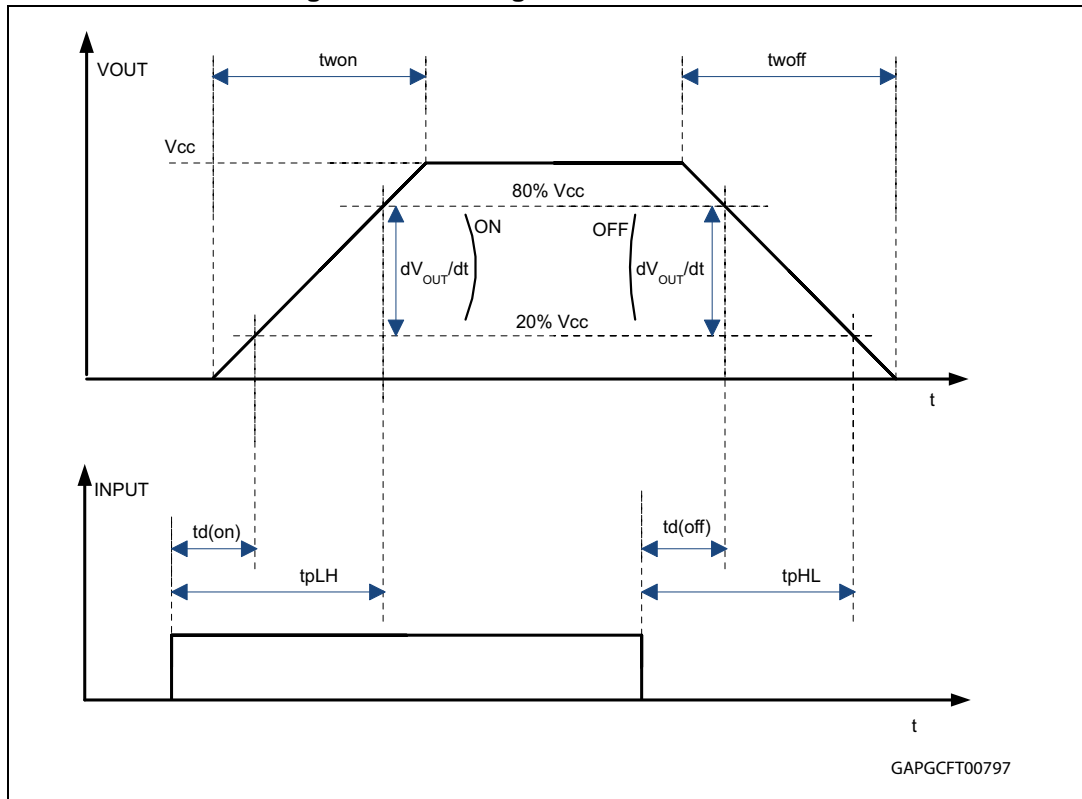


Figure 7. CurrentSense timings (current sense mode)

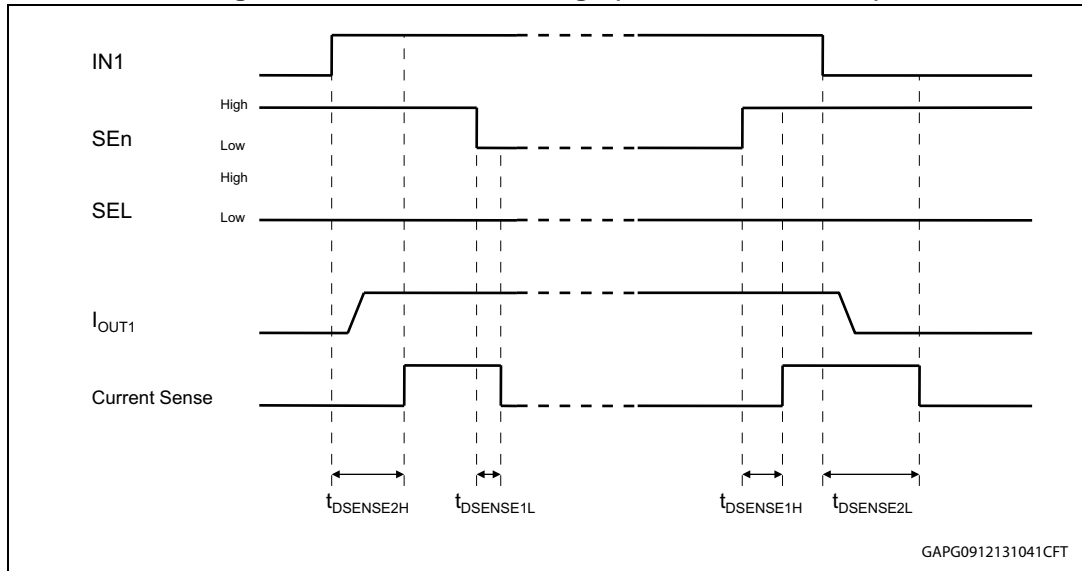


Figure 8. T_{DSTKON}

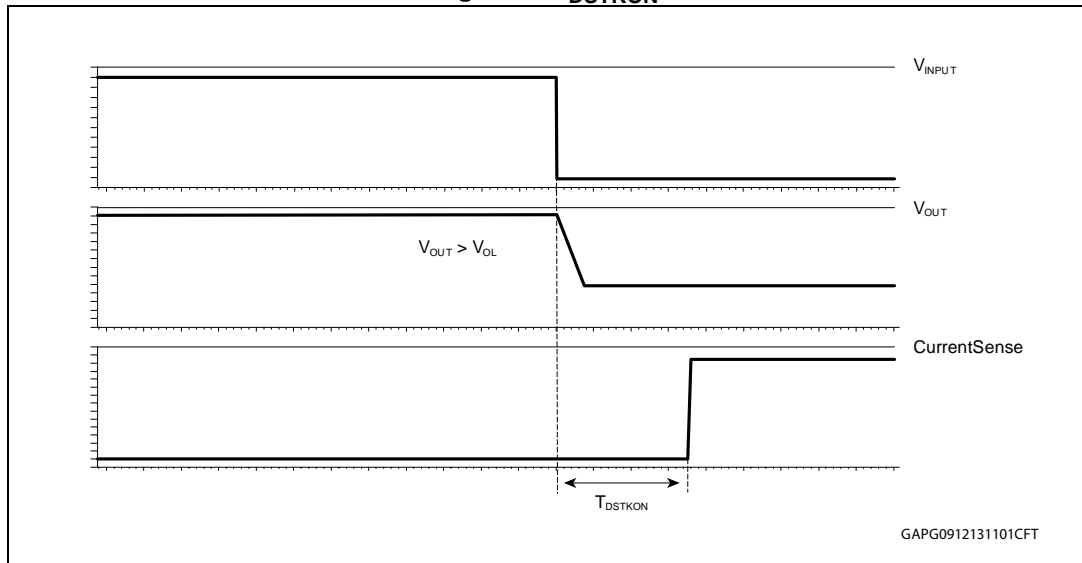


Table 10. Truth table

Mode	Conditions	IN_x	SEn	SEL	OUT_x	CurrentSense	Comments
Standby	All logic inputs low	L	L	L	L	Hi-Z	Low quiescent current consumption
Normal	Nominal load connected; $T_j < 150^\circ\text{C}$	L	Refer to Table 11		L	Refer to Table 11	Outputs configured for auto-restart
		H			H		Outputs configured for Latch-off
		H			H		
Overload	Overload or short to GND causing: $T_j > T_{TSD}$ or $\Delta T_j > \Delta T_{j_SD}$	L	Refer to Table 11		L	Refer to Table 11	Output cycles with temperature hysteresis
		H			H		Output latches-off
		H			L		
Under-voltage	$V_{CC} < V_{USD}$ (falling)	X	X	X	L L	Hi-Z Hi-Z	Re-start when $V_{CC} > V_{USD} + V_{USDhyst}$ (rising)
OFF-state diagnostics	Short to V_{CC}	L	Refer to Table 11		H	Refer to Table 11	
	Open-load	L			H		External pull-up
Negative output voltage	Inductive loads turn-off	L	Refer to Table 11		$< 0\text{ V}$	Refer to Table 11	

Table 11. CurrentSense multiplexer addressing

SEn	SEL	MUX channel	CurrentSense output			
			Nomal mode	Overload	OFF-state diag.	Negative output
L	X		Hi-Z			
H	L	Channel 0 diagnostic	$I_{SENSE} = 1/K * I_{OUT0}$	$V_{SENSE} = V_{SENSEH}$	$V_{SENSE} = V_{SENSEH}$	Hi-Z
H	H	Channel 1 diagnostic	$I_{SENSE} = 1/K * I_{OUT1}$	$V_{SENSE} = V_{SENSEH}$	$V_{SENSE} = V_{SENSEH}$	Hi-Z

2.4 Waveforms

Figure 9. Standby mode activation

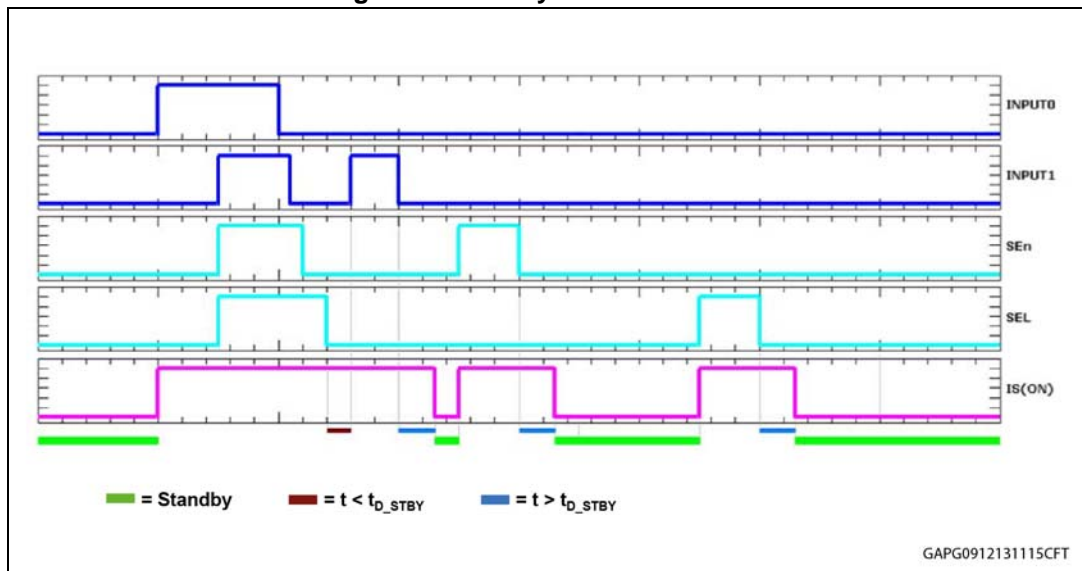
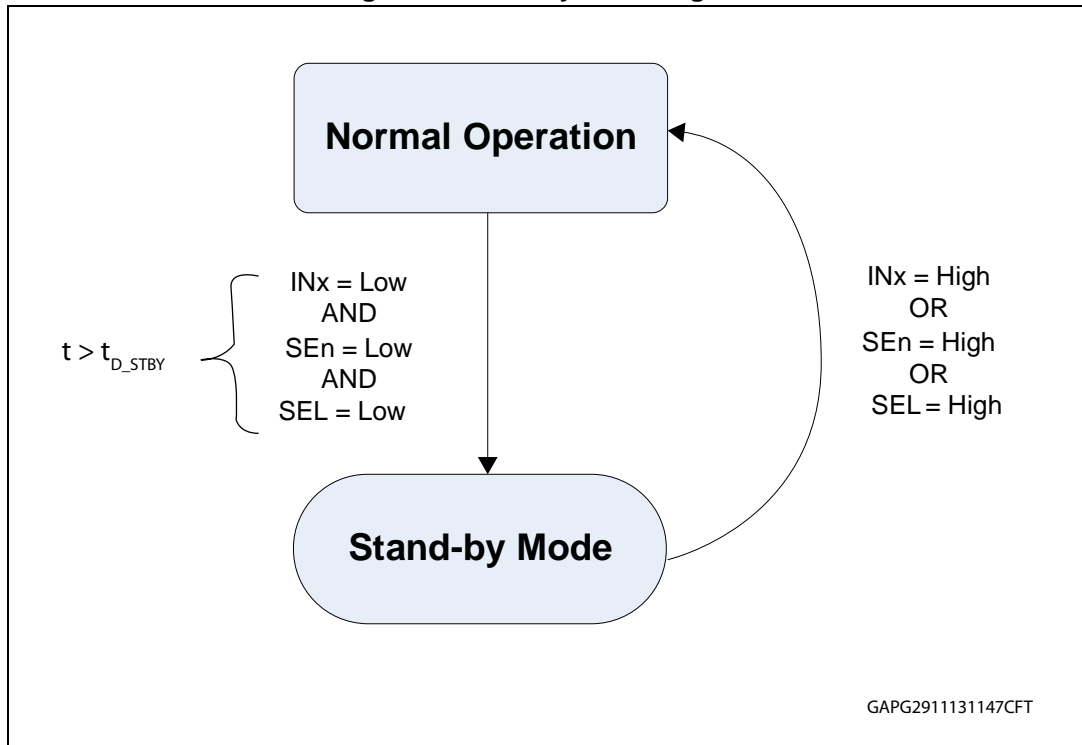


Figure 10. Standby state diagram



2.5 Electrical characteristics curves

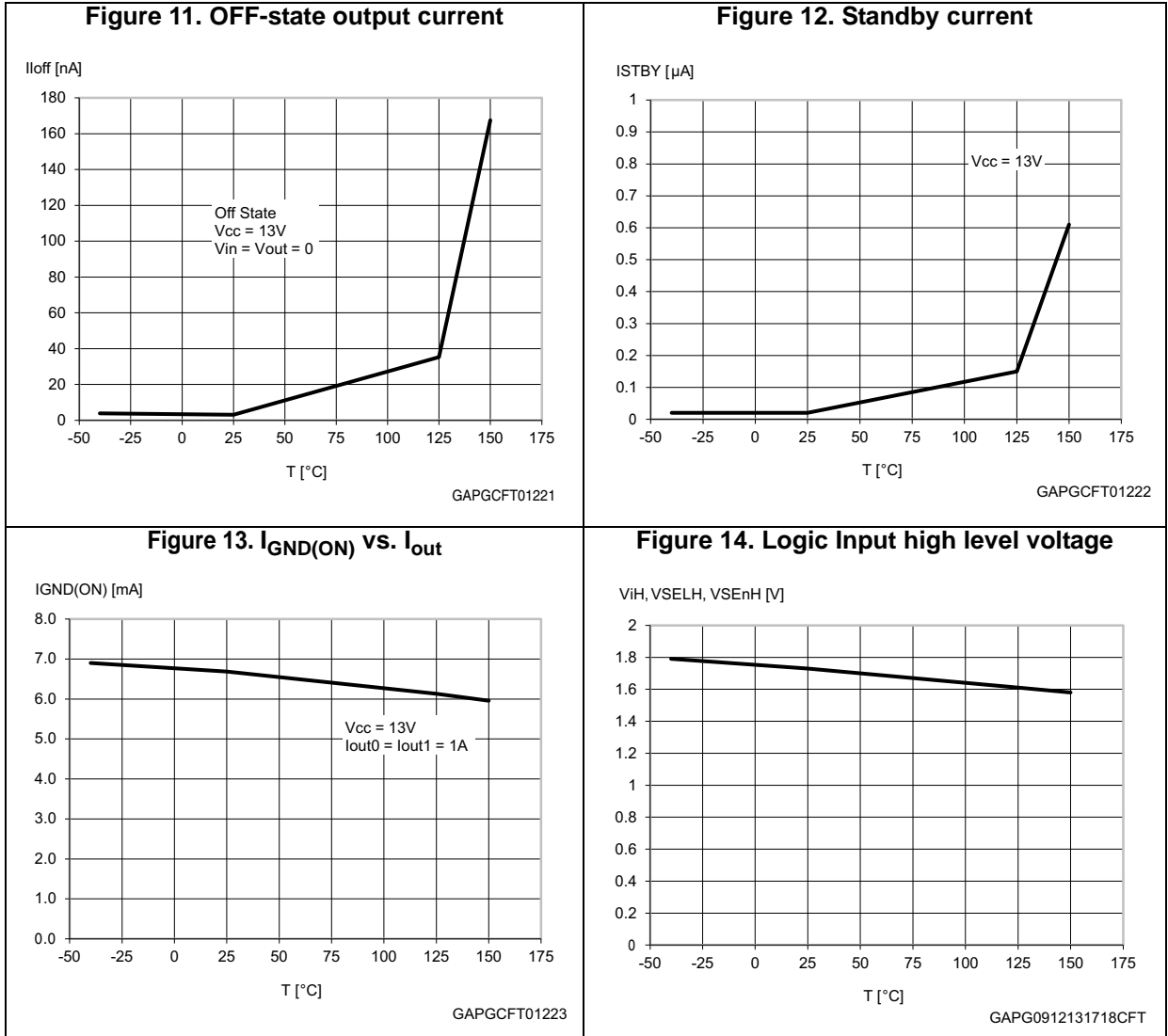


Figure 15. Logic Input low level voltage

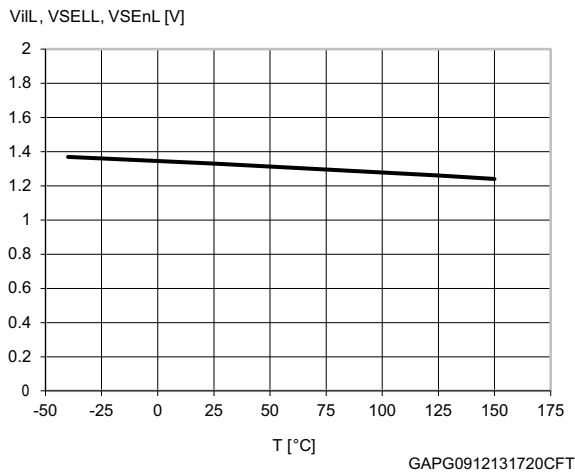


Figure 16. High level logic input current

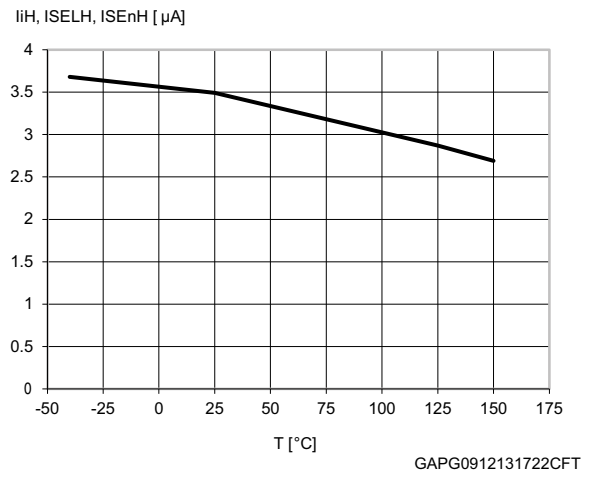


Figure 17. Low level logic input current

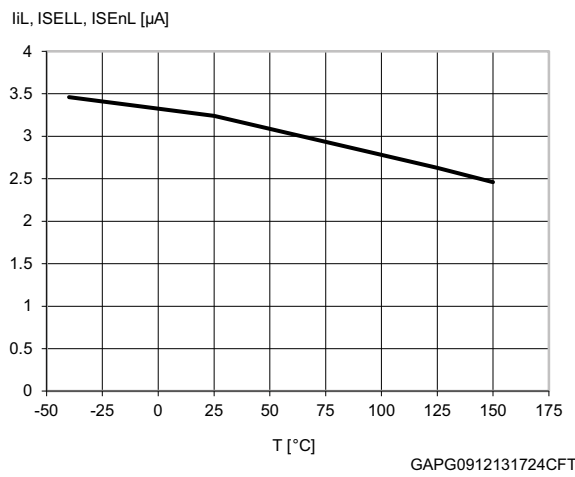


Figure 18. Logic Input hysteresis voltage

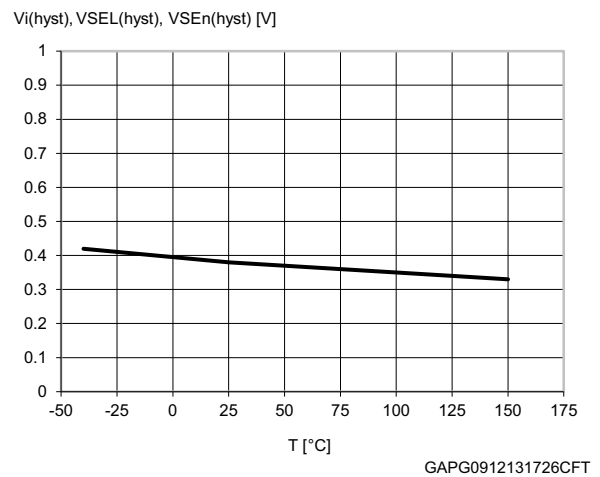


Figure 19. Undervoltage shutdown

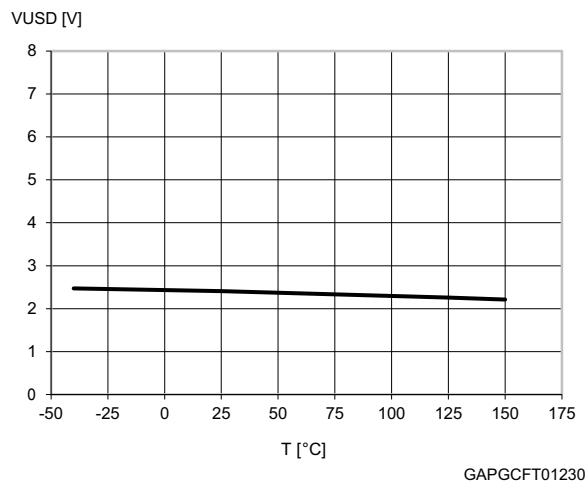
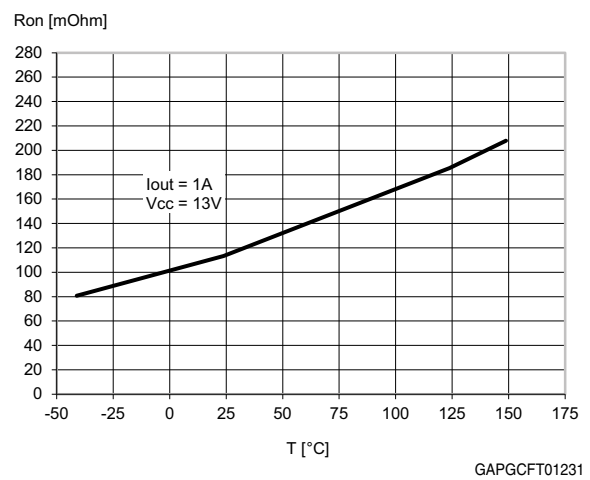


Figure 20. On-state resistance vs. T_{case}



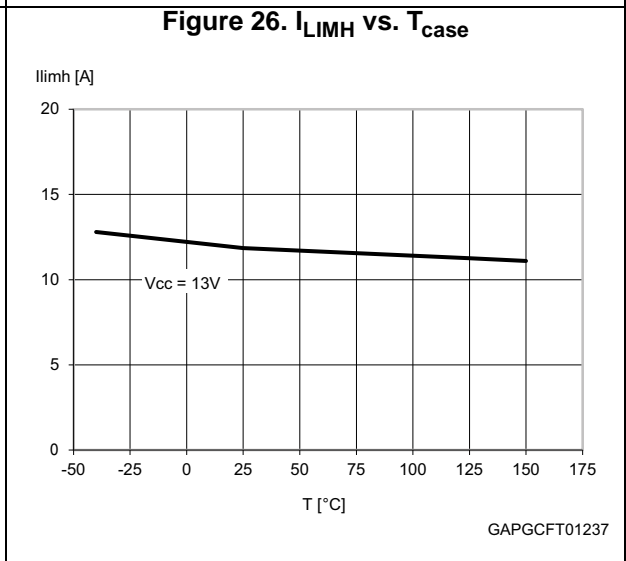
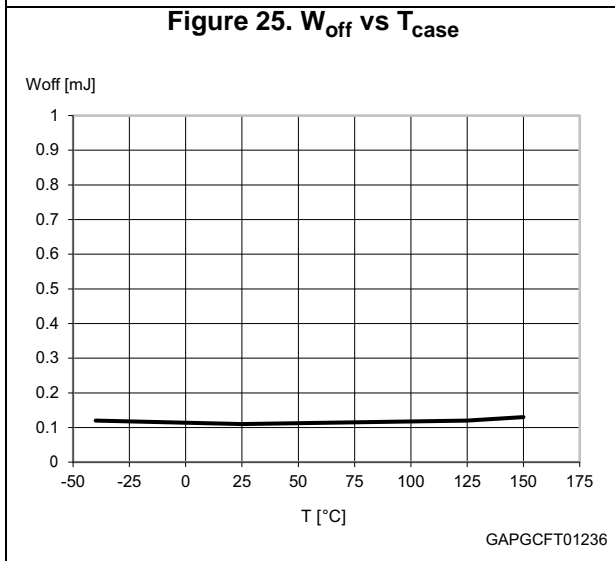
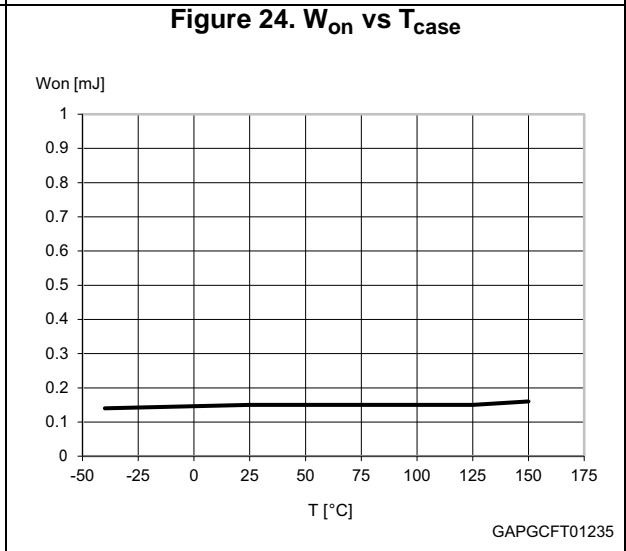
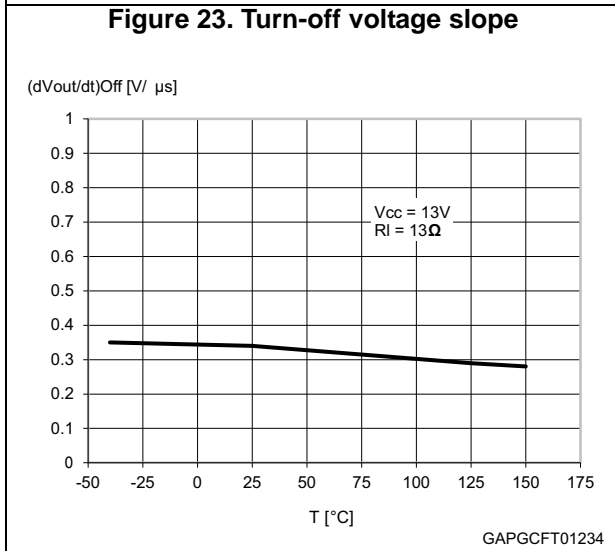
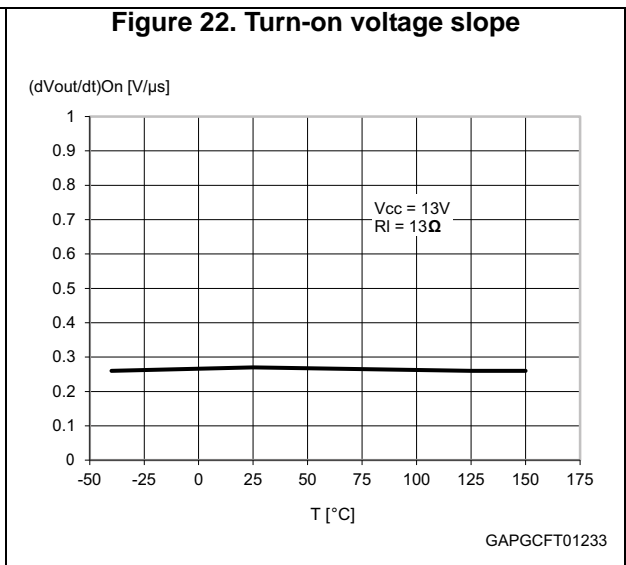
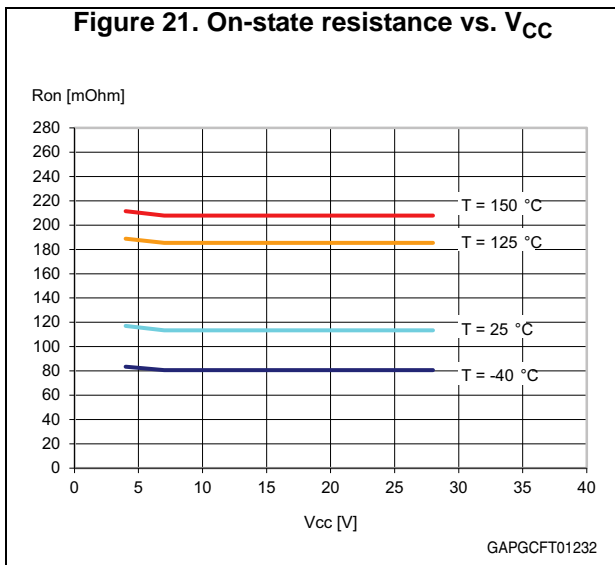


Figure 27. OFF-state open-load voltage detection threshold

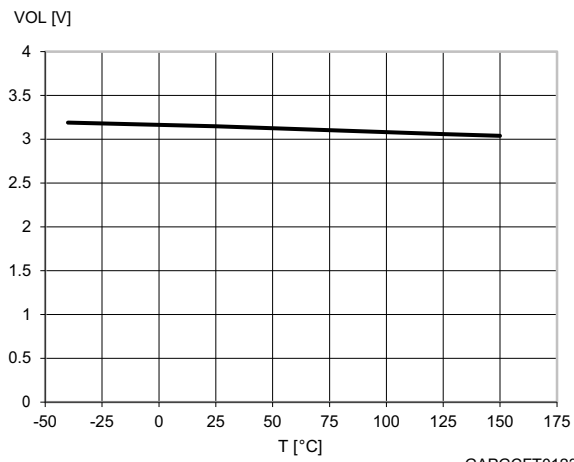


Figure 28. V_{sense} clamp vs T_{case}

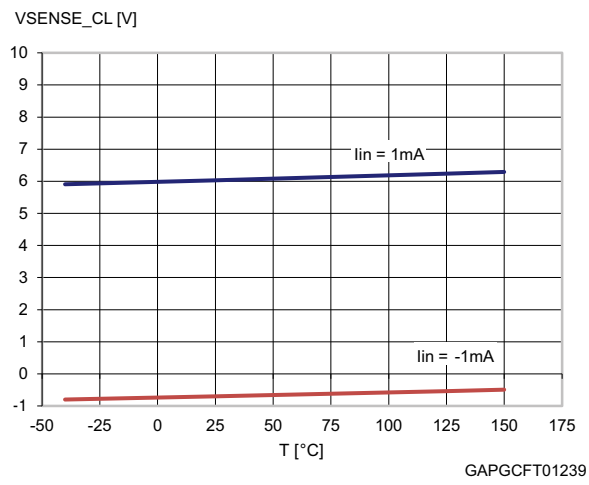
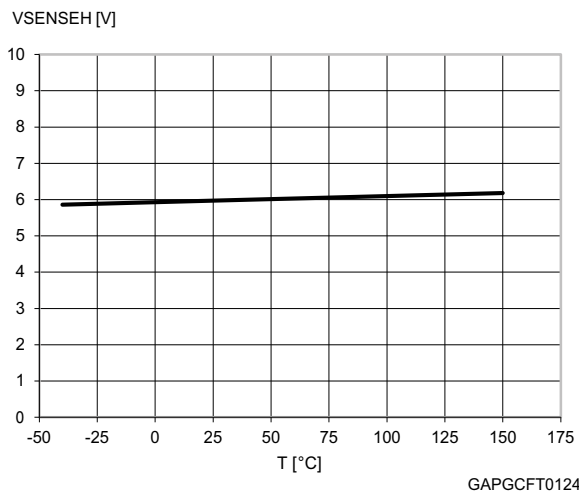


Figure 29. V_{senseh} vs T_{case}



3 Protections

3.1 Power limitation

The basic working principle of this protection consists of an indirect measurement of the junction temperature swing ΔT_j through the direct measurement of the spatial temperature gradient on the device surface in order to automatically shut off the output MOSFET as soon as ΔT_j exceeds the safety level of ΔT_{j_SD} . The output MOSFET switches on and cycles with a thermal hysteresis according to the maximum instantaneous power which can be handled. The protection prevents fast thermal transient effects and, consequently, reduces thermo-mechanical fatigue.

3.2 Thermal shutdown

In case the junction temperature of the device exceeds the maximum allowed threshold (typically 175°C), it automatically switches off and the diagnostic indication is triggered. The device switches on again as soon as its junction temperature drops to T_R .

3.3 Current limitation

The device is equipped with an output current limiter in order to protect the silicon as well as the other components of the system (e.g. bonding wires, wiring harness, connectors, loads, etc.) from an excessive current flow. Consequently, in case of short circuit, overload or during load power-up, the output current is clamped to a safety level, I_{LIMH} , by operating the output power MOSFET in the active region.

3.4 Negative voltage clamp

In case the device drives inductive load, the output voltage reaches negative value during turn off. A negative voltage clamp structure limits the maximum negative voltage to a certain value, V_{DEMAG} (see [Table 8](#)), allowing the inductor energy to be dissipated without damaging the device.

4.1.1 Diode (D_{GND}) in the ground line

A resistor (typ. $R_{GND} = 4.7 \text{ k}\Omega$) should be inserted in parallel to D_{GND} if the device drives an inductive load.

This small signal diode can be safely shared amongst several different HSDs. Also in this case, the presence of the ground network produces a shift ($\approx 600 \text{ mV}$) in the input threshold and in the status output values if the microprocessor ground is not common to the device ground. This shift does not vary if more than one HSD shares the same diode/resistor network.

4.2 Immunity against transient electrical disturbances

The immunity of the device against transient electrical emissions, conducted along the supply lines and injected into the V_{CC} pin, is tested in accordance with ISO 7637-2:2011 (E) and ISO 16750-2:2010.

The related function performance status classification is shown in [Table 12](#).

Test pulses are applied directly to DUT (Device Under Test) both in ON and OFF-state and in accordance to ISO 7637-2:2011(E), chapter 4. The DUT is intended as the present device only, without components and accessed through V_{CC} and GND terminals.

Status II is defined in ISO 7637-1 Function Performance Status Classification (FPSC) as follows: "The function does not perform as designed during the test but returns automatically to normal operation after the test".

Table 12. ISO 7637-2 - electrical transient conduction along supply line

Test Pulse 2011(E)	Test pulse severity level with Status II functional performance status		Minimum number of pulses or test time	Burst cycle / pulse repetition time		Pulse duration and pulse generator internal impedance
	Level	$U_S^{(1)}$		min	max	
1	III	-112V	500 pulses	0,5 s		2ms, 10 Ω
2a	III	+55V	500 pulses	0,2 s	5 s	50 μ s, 2 Ω
3a	IV	-220V	1h	90 ms	100 ms	0.1 μ s, 50 Ω
3b	IV	+150V	1h	90 ms	100 ms	0.1 μ s, 50 Ω
4 ⁽²⁾	IV	-7V	1 pulse			100ms, 0.01 Ω
Load dump according to ISO 16750-2:2010						
Test B ⁽³⁾		40V	5 pulse	1 min		400ms, 2 Ω

1. U_S is the peak amplitude as defined for each test pulse in ISO 7637-2:2011(E), chapter 5.6.

2. Test pulse from ISO 7637-2:2004(E).

3. With 40 V external suppressor referred to ground ($-40^\circ\text{C} < T_j < 150^\circ\text{C}$).

4.3 MCU I/Os protection

If a ground protection network is used and negative transients are present on the V_{CC} line, the control pins will be pulled negative. ST suggests to insert a resistor (R_{prot}) in line both to prevent the microcontroller I/O pins from latching-up and to protect the HSD inputs.

The value of these resistors is a compromise between the leakage current of microcontroller and the current required by the HSD I/Os (Input levels compatibility) with the latch-up limit of microcontroller I/Os.

Equation 1

$$V_{CCpeak}/I_{latchup} \leq R_{prot} \leq (V_{OH\mu C} - V_{IH} - V_{GND}) / I_{IHmax}$$

Calculation example:

For $V_{CCpeak} = -150\text{ V}$; $I_{latchup} \geq 20\text{ mA}$; $V_{OH\mu C} \geq 4.5\text{ V}$

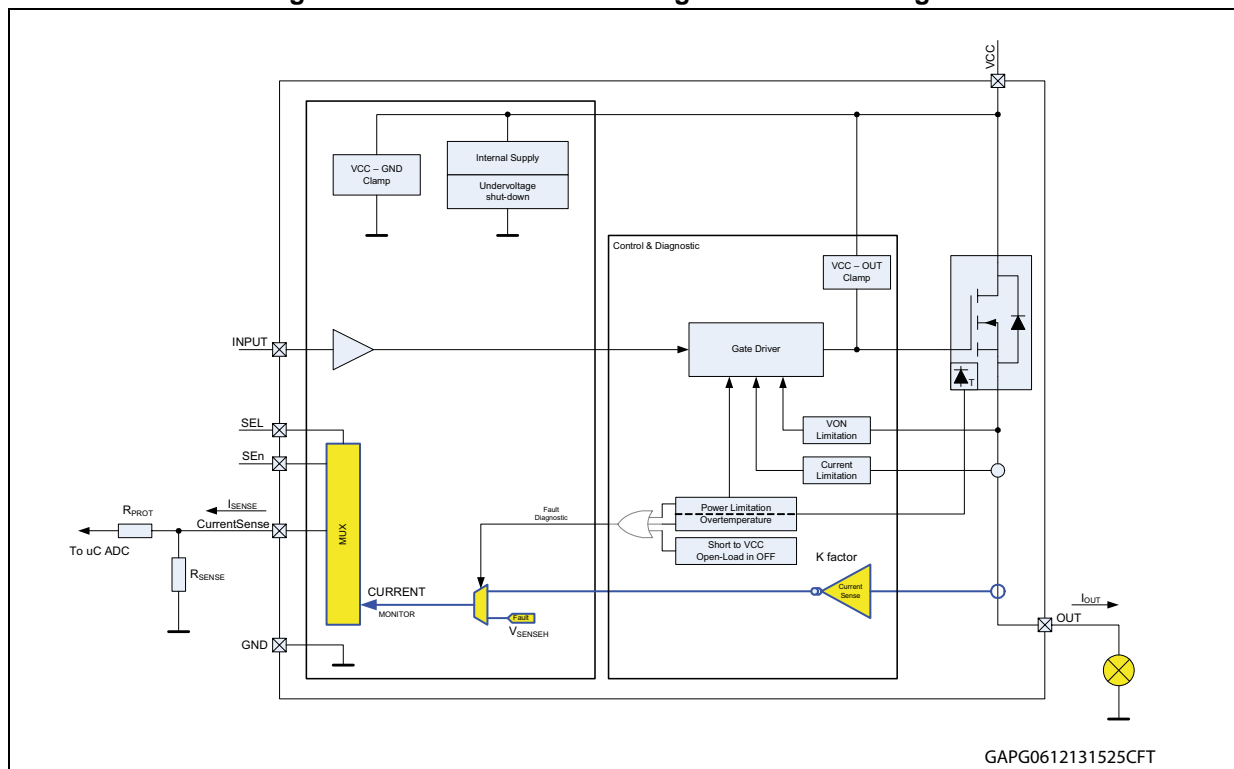
$$7.5\text{ k}\Omega \leq R_{prot} \leq 140\text{ k}\Omega.$$

Recommended values: $R_{prot} = 15\text{ k}\Omega$

4.4 CurrentSense - analog current sense

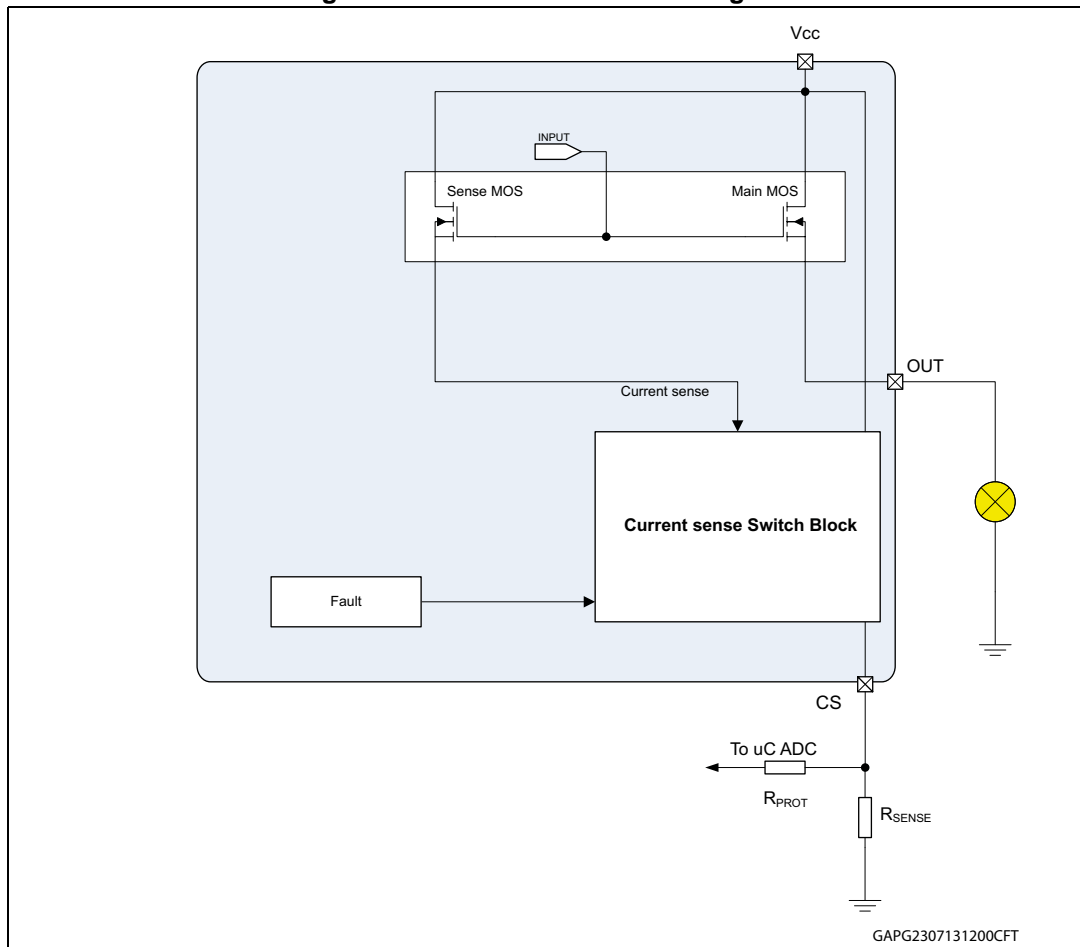
Diagnostic information on device and load status are provided by an analog output pin (CurrentSense) delivering a current mirror of channel output current.

Figure 32. CurrentSense and diagnostic – block diagram



4.4.1 Principle of CurrentSense signal generation

Figure 33. CurrentSense block diagram



Current monitor

This output is capable of providing:

- **Current mirror proportional to the load current in normal operation**, delivering current proportional to the load according to known ratio named **K**
- **Diagnostics flag in fault conditions** delivering fixed voltage V_{SENSEH}

The current delivered by the current sense circuit, I_{SENSE} , can be easily converted to a voltage V_{SENSE} by using an external sense resistor, R_{SENSE} , allowing continuous load monitoring and abnormal condition detection.

Normal operation (channel ON, no fault, SEn active)

While device is operating in normal conditions (no fault intervention), V_{SENSE} calculation can be done using simple equations

Current provided by CurrentSense output: $I_{SENSE} = I_{OUT}/K$

Voltage on R_{SENSE} : $V_{SENSE} = R_{SENSE} \cdot I_{SENSE} = R_{SENSE} \cdot I_{OUT}/K$

Where:

- V_{SENSE} is voltage measurable on R_{SENSE} resistor
- I_{SENSE} is current provided from CurrentSense pin in current output mode
- I_{OUT} is current flowing through output
- K factor represents the ratio between PowerMOS cells and SenseMOS cells; its spread includes geometric factor spread, current sense amplifier offset and process parameters spread of overall circuitry specifying ratio between I_{OUT} and I_{SENSE} .

Failure flag indication

In case of power limitation/overtemperature, the fault is indicated by the CurrentSense pin which is switched to a “current limited” voltage source, V_{SENSEH} (see [Table 9](#)).

In any case, the current sourced by the CurrentSense in this condition is limited to I_{SENSEH} (see [Table 9](#)).

The typical behavior in case of overload or hard short circuit is shown in [Figure 9](#).

Figure 34. Analogue HSD – open-load detection in off-state

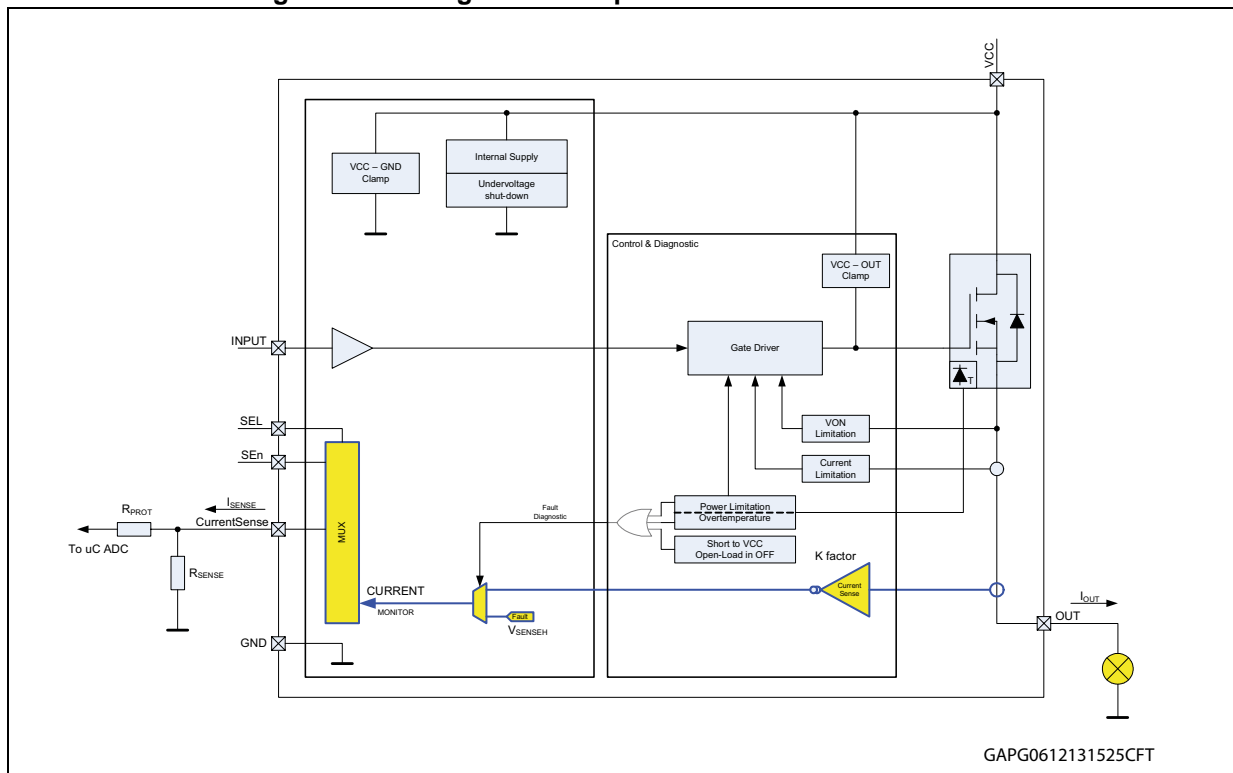


Figure 35. Open-load / short to V_{CC} condition

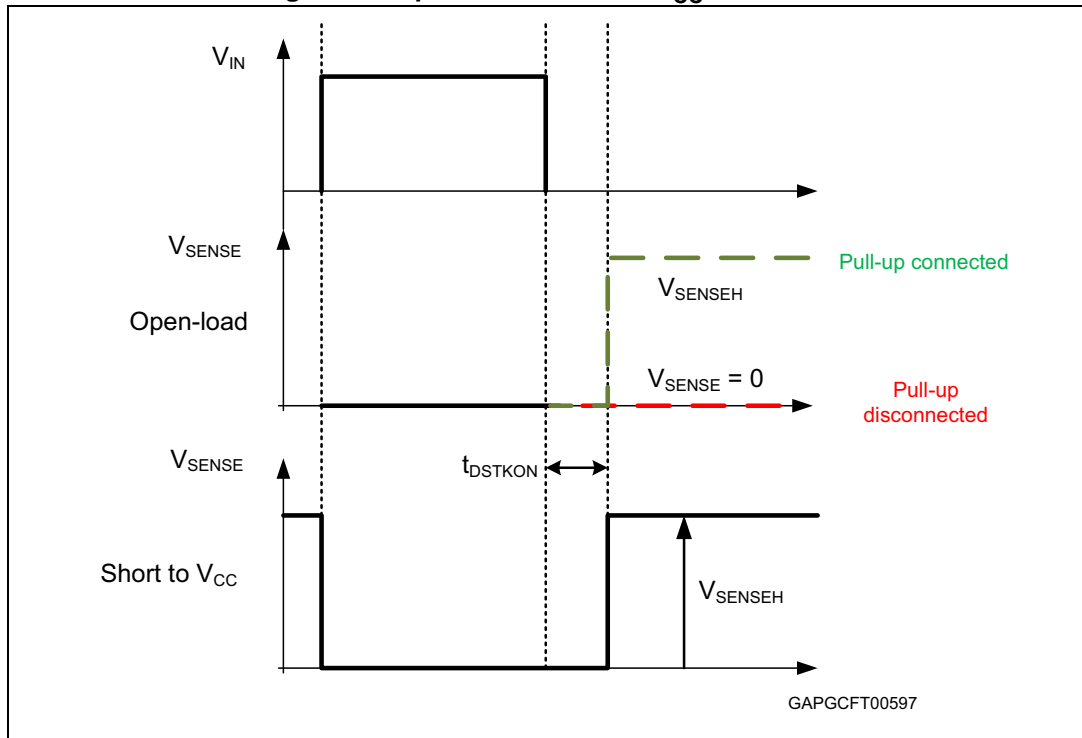


Table 13. CurrentSense pin levels in off-state

Condition	Output	CurrentSense	SEn
Open-load	$V_{OUT} > V_{OL}$	Hi-Z	L
		V_{SENSEH}	H
	$V_{OUT} < V_{OL}$	Hi-Z	L
		0	H
Short to V_{CC}	$V_{OUT} > V_{OL}$	Hi-Z	L
		V_{SENSEH}	H
Nominal	$V_{OUT} < V_{OL}$	Hi-Z	L
		0	H

4.4.2 Short to V_{CC} and OFF-state open-load detection

Short to V_{CC}

A short circuit between V_{CC} and output is indicated by the relevant current sense pin set to V_{SENSEH} during the device off-state. Small or no current is delivered by the current sense during the on-state depending on the nature of the short circuit.

OFF-state open-load with external circuitry

Detection of an open-load in off mode requires an external pull-up resistor R_{PU} connecting the output to a positive supply voltage V_{PU} .

It is preferable V_{PU} to be switched off during the module standby mode in order to avoid the overall standby current consumption to increase in normal conditions, i.e. when load is connected.

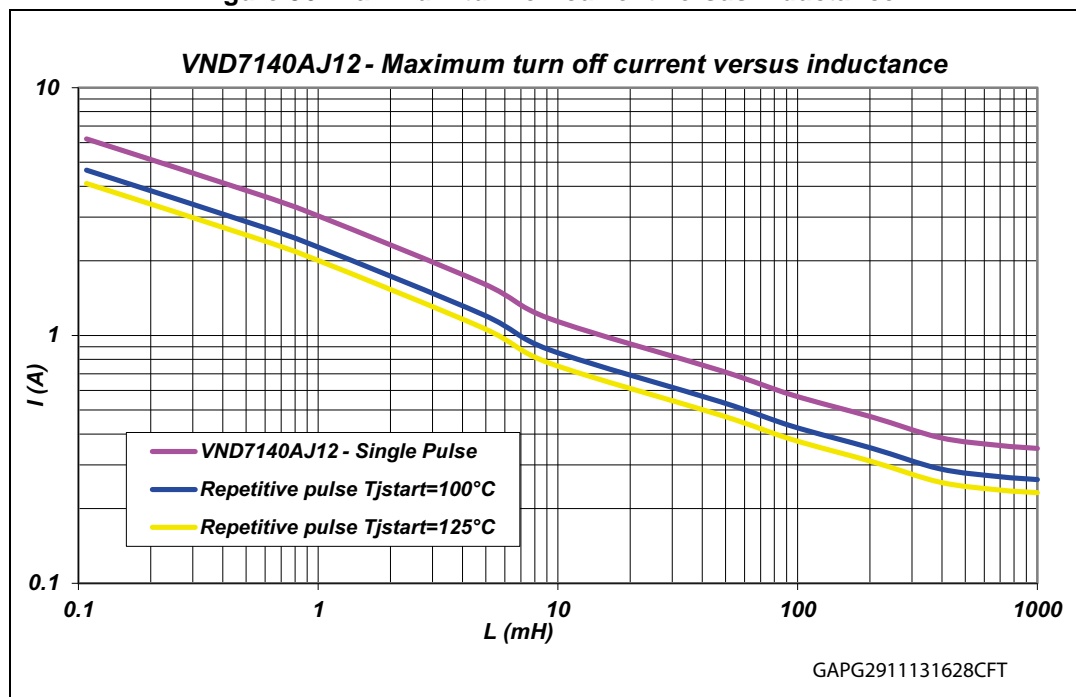
R_{PU} must be selected in order to ensure $V_{OUT} > V_{OLmax}$ in accordance with the following equation:

Equation 2

$$R_{PU} < \frac{V_{PU} - 4}{I_{L(off2)min @ 4V}}$$

4.5 Maximum demagnetization energy ($V_{CC} = 16 V$)

Figure 36. Maximum turn off current versus inductance



- Values are generated with $R_L = 0 \Omega$.
In case of repetitive pulses, T_{jstart} (at the beginning of each demagnetization) of every pulse must not exceed the temperature specified above for curves A and B.

5 Package and PCB thermal data

5.1 PowerSSO-12 thermal data

Figure 37. PowerSSO-12 on two-layers PCB (2s0p to JEDEC JESD 51-5)

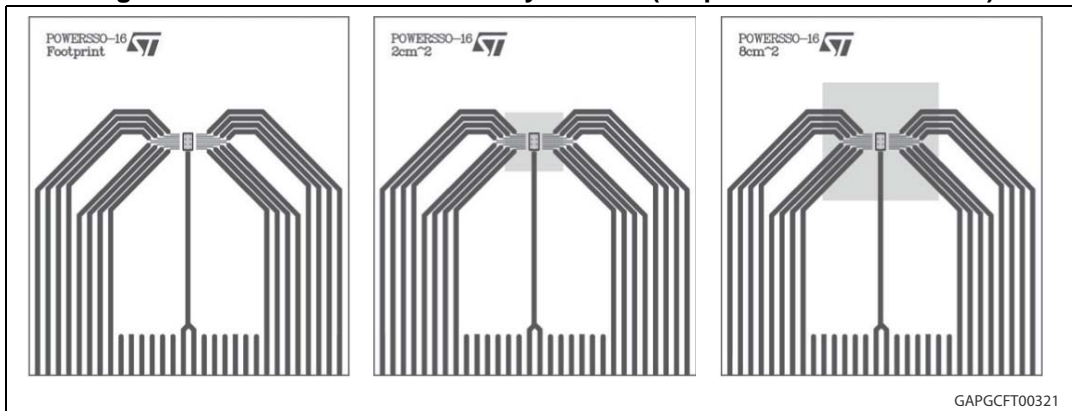


Figure 38. PowerSSO-12 on four-layers PCB (2s2p to JEDEC JESD 51-7)

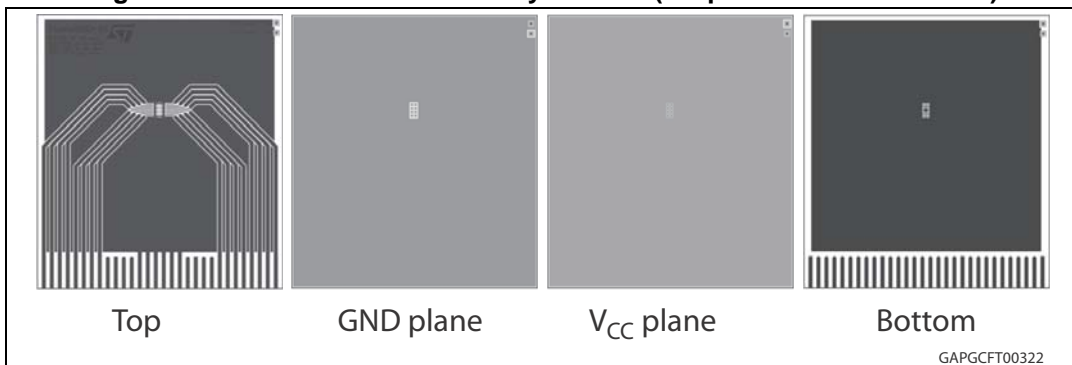


Table 14. PCB properties

Dimension	Value
Board finish thickness	1.6 mm +/- 10%
Board dimension	77 mm x 86 mm
Board Material	FR4
Copper thickness (top and bottom layers)	0.070 mm
Copper thickness (inner layers)	0.035 mm
Thermal vias separation	1.2 mm
Thermal via diameter	0.3 mm +/- 0.08 mm
Copper thickness on vias	0.025 mm
Footprint dimension (top layer)	2.2 mm x 3.9 mm
Heatsink copper area dimension (bottom layer)	Footprint, 2 cm ² or 8 cm ²

Figure 39. PowerSSO-12 $R_{thj-amb}$ vs PCB copper area in open box free air condition

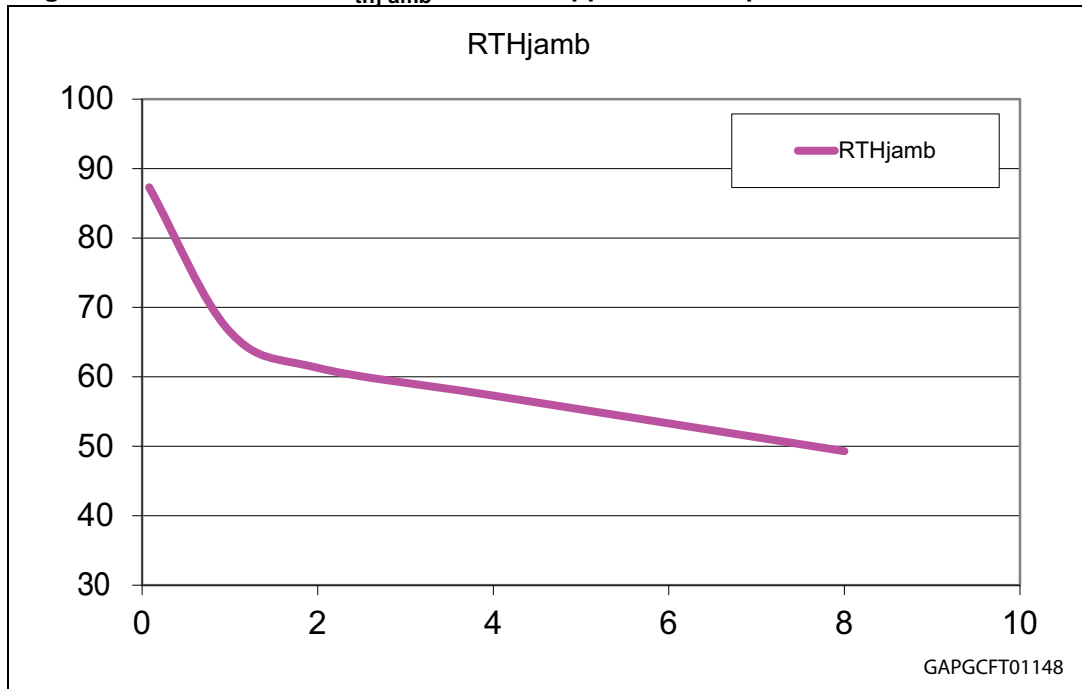
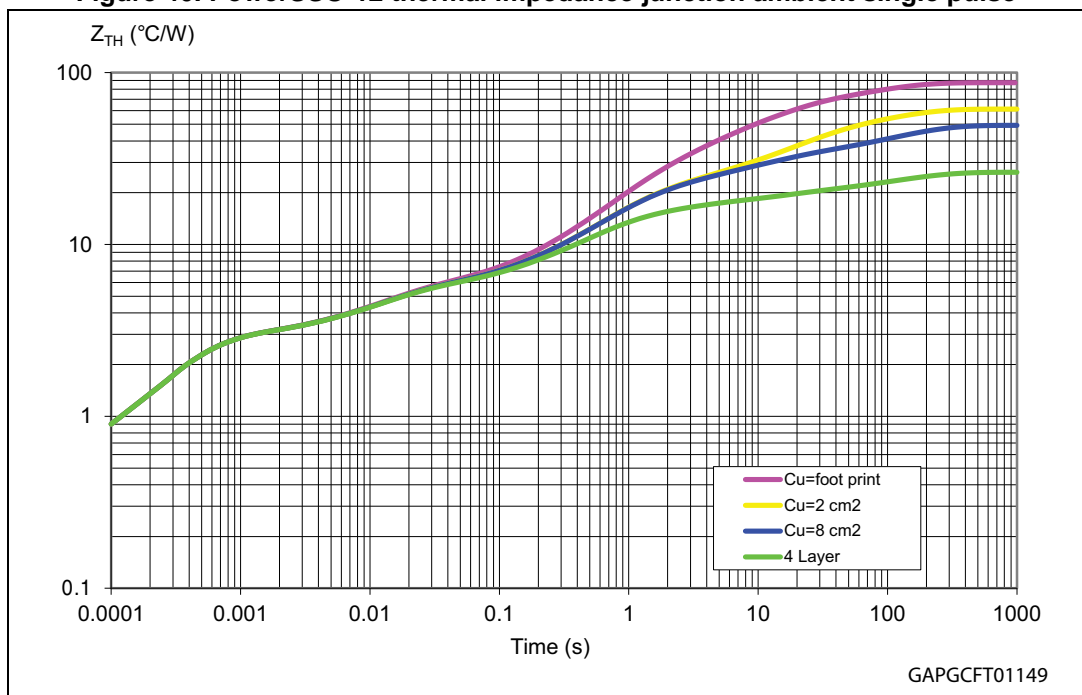


Figure 40. PowerSSO-12 thermal impedance junction ambient single pulse

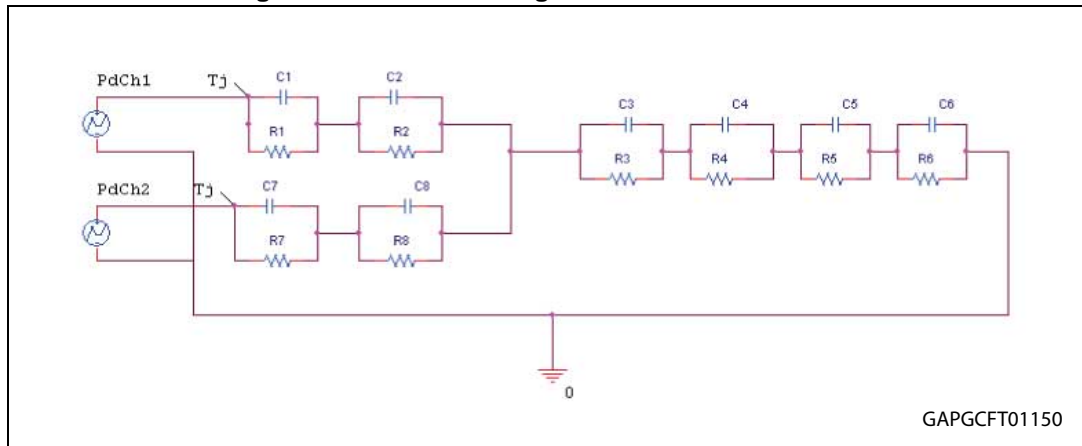


Equation 3: pulse calculation formula

$$Z_{TH\delta} = R_{TH} \cdot \delta + Z_{THtp}(1 - \delta)$$

where $\delta = t_p/T$

Figure 41. Thermal fitting model for PowerSSO-12



GAPGCFT01150

1. The fitting model is a simplified thermal tool and is valid for transient evolutions where the embedded protections (power limitation or thermal cycling during thermal shutdown) are not triggered.

Table 15. Thermal parameters

Area/island (cm ²)	Footprint	2	8	4L
R1 = R7 (°C/W)	2.8			
R2 = R8 (°C/W)	2.5			
R3 (°C/W)	10	10	10	7
R4 (°C/W)	16	6	6	4
R5 (°C/W)	30	20	10	3
R6 (°C/W)	26	20	18	7
C1 = C7 (W.s/°C)	0.00012			
C2 = C8 (W.s/°C)	0.005			
C3 (W.s/°C)	0.07			
C4 (W.s/°C)	0.2	0.3	0.3	0.4
C5 (W.s/°C)	0.4	1	1	4
C6 (W.s/°C)	3	5	7	18

6 Package information

6.1 ECOPACK®

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com.

ECOPACK® is an ST trademark.

6.2 PowerSSO-12 package information

Figure 42. PowerSSO-12 package dimensions

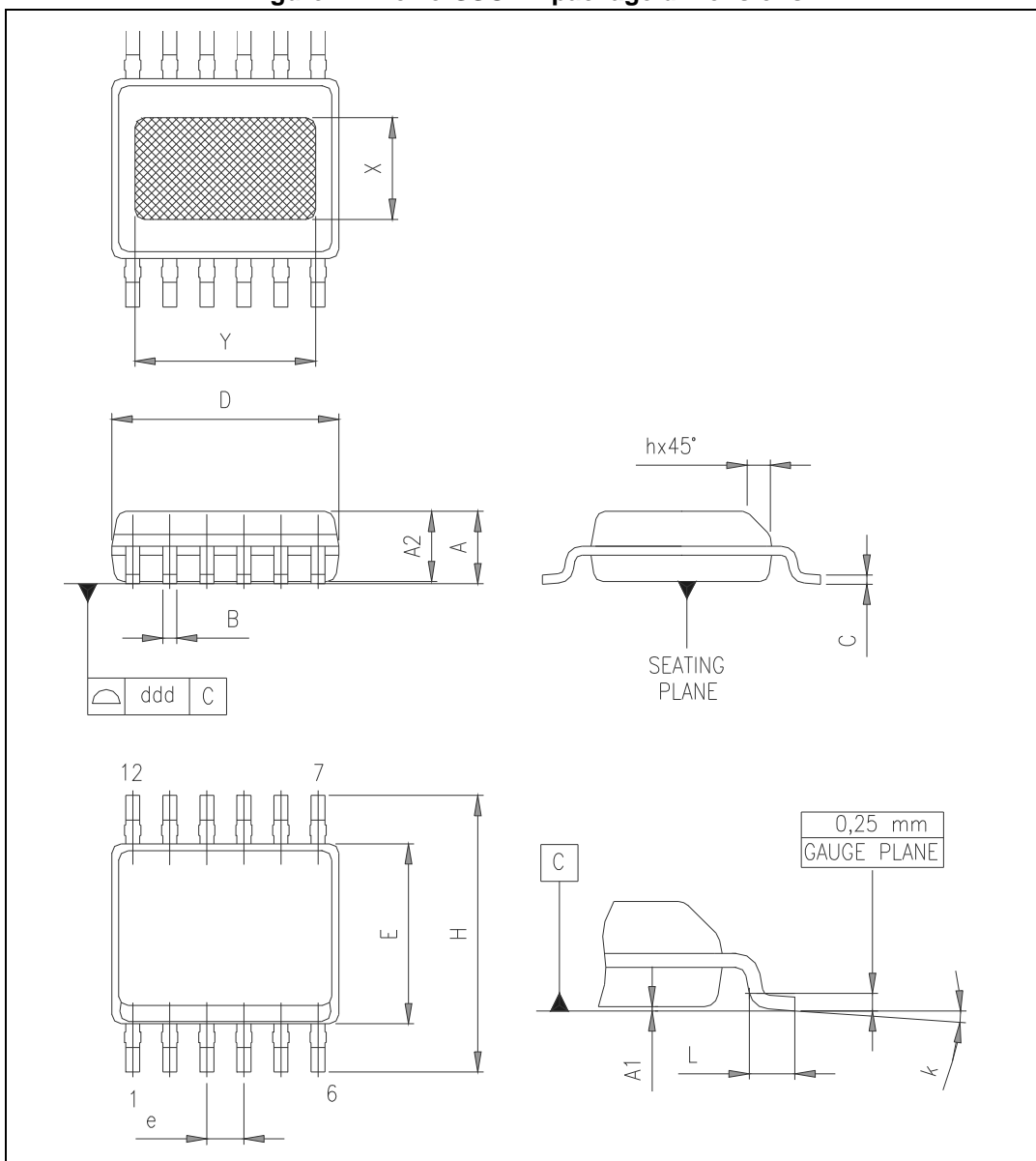


Table 16. PowerSSO-12 mechanical data

Symbol	Millimeters		
	Min.	Typ.	Max.
A	1.250		1.700
A1	0.000		0.100
A2	1.100		1.600
B	0.230		0.410
C	0.190		0.250
D	4.800		5.000
E	3.800		4.000
e		0.800	
H	5.800		6.200
h	0.250		0.500
L	0.400		1.270
k	0°		8°
X	2.200		2.800
Y	2.900		3.500
ddd			0.100

7 Order codes

Table 17. Device summary

Package	Order codes	
	Tube	Tape and reel
PowerSSO-12	—	VND7140AJ12TR-E

8 Revision history

Table 18. Revision history

Date	Revision	Changes
30-Jan-2014	1	Initial release
05-Mar-2014	2	Updated <i>Figure 2: Configuration diagram (top view)</i>
26-Mar-2015	3	Table <i>Table 9: CurrentSense (7 V < V_{CC} < 18 V; -40°C < T_j < 150°C)</i> : – K _{OL} , K _{LED} , K ₀ , K ₁ : updated values Updated <i>Figure 4: I_{OUT}/I_{SENSE} versus I_{OUT}</i> and <i>Figure 5: Current sense accuracy versus I_{OUT}</i> Updated <i>Table 16: PowerSSO-12 mechanical data</i> and <i>Table 17: Device summary</i>

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